

Title: METHODS OF NANOSTRUCTURE FORMATION AND SHAPE SELECTION

Inventors: Younan Xia and Yugan Sun

Docket No.: 53433/2 Serial No.: 10/732,910 Filed: 12/09/2003

REPLACEMENT SHEET (Set A)

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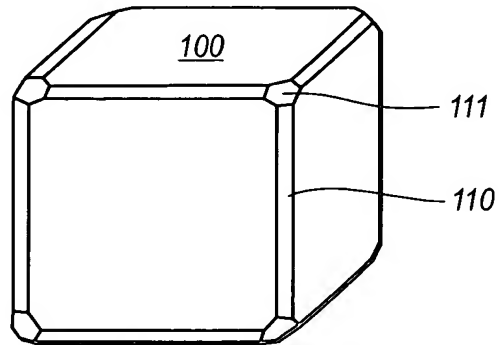


Fig. 1

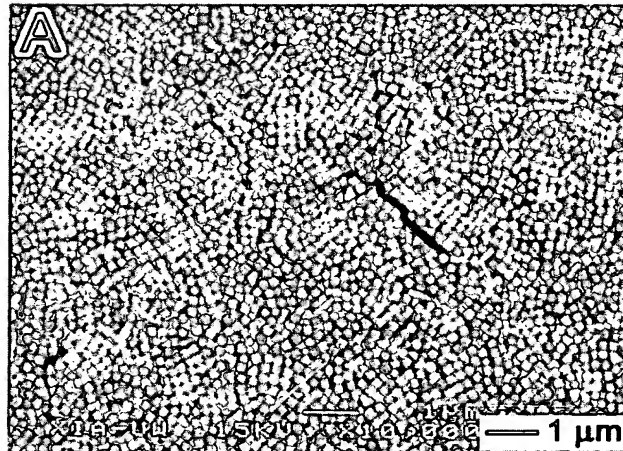


Fig. 2A

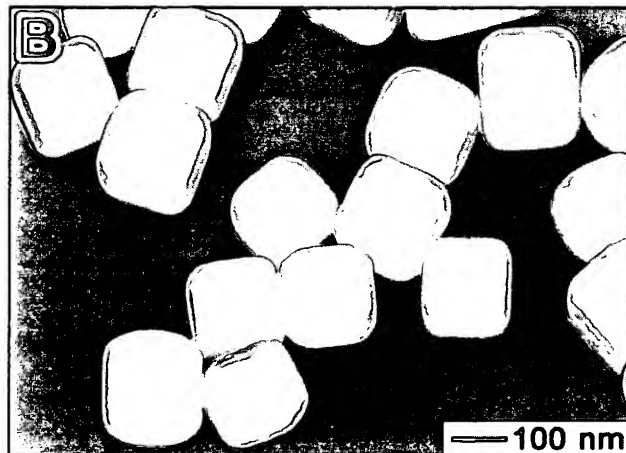


Fig. 2B

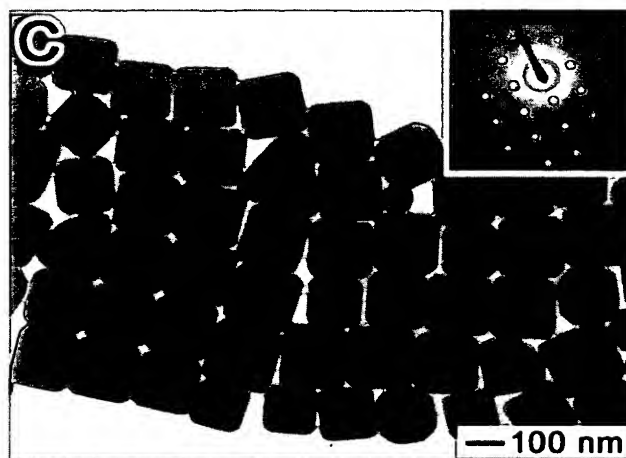


Fig. 2C

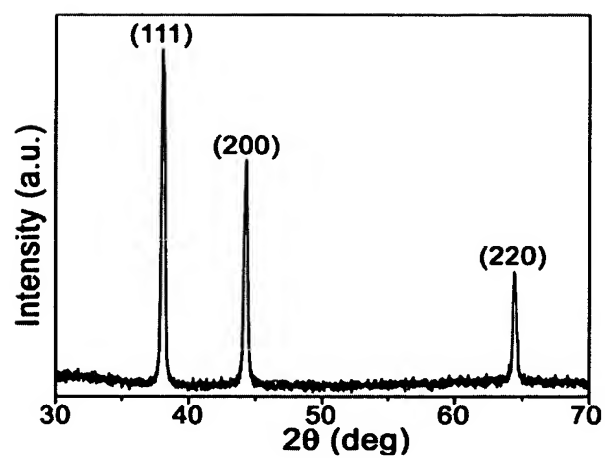


Fig. 2D

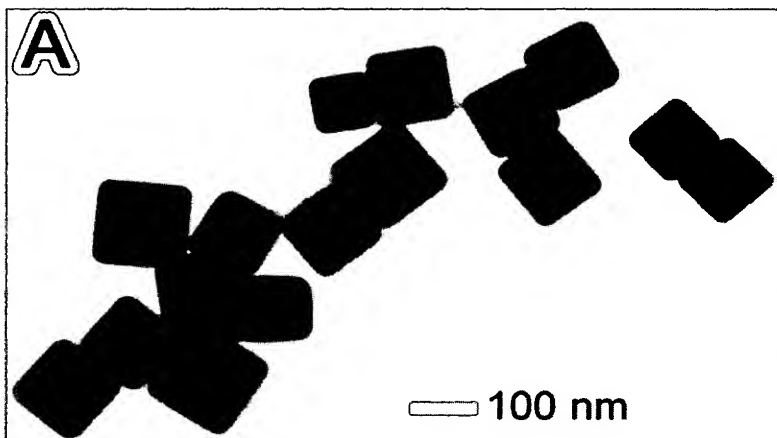


Fig. 3A

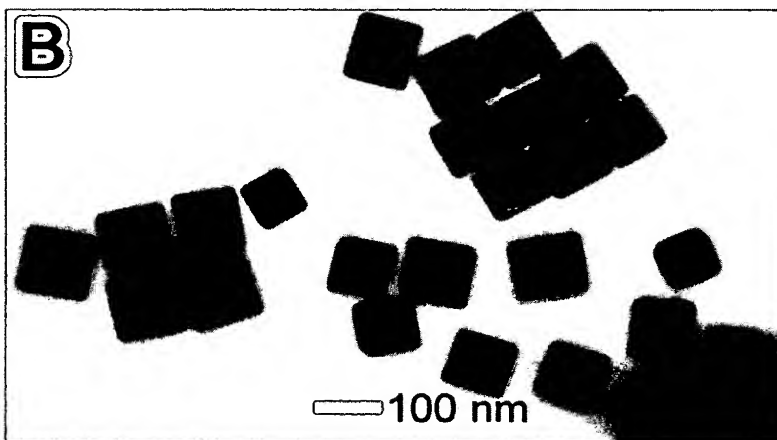


Fig. 3B

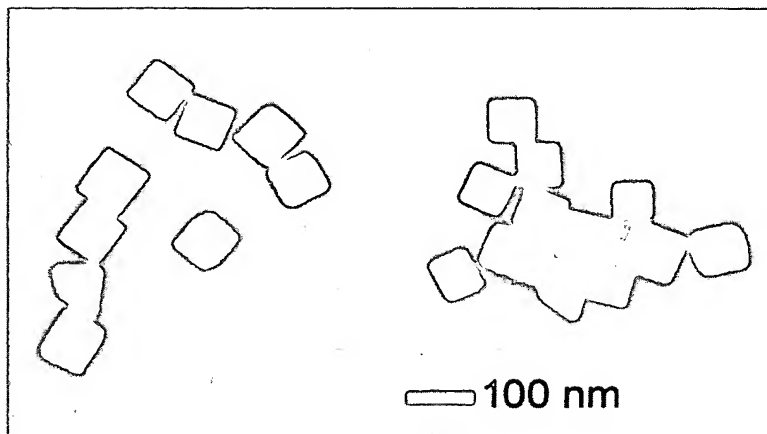


Fig. 4

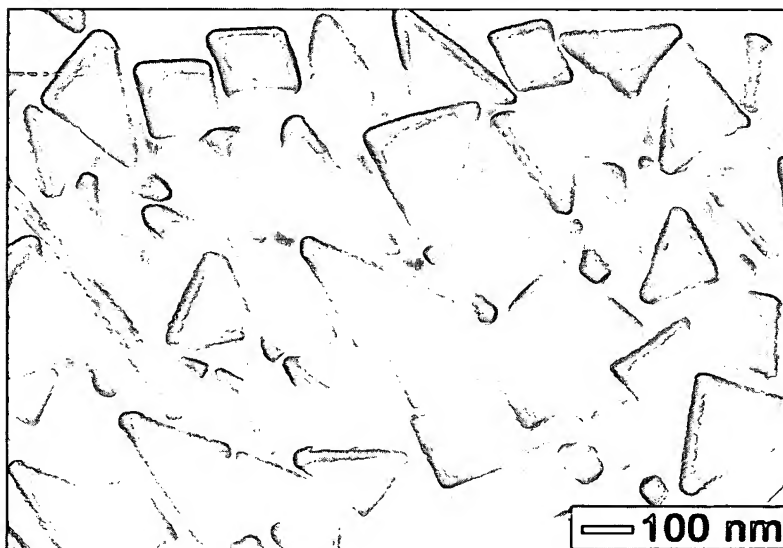


Fig. 5

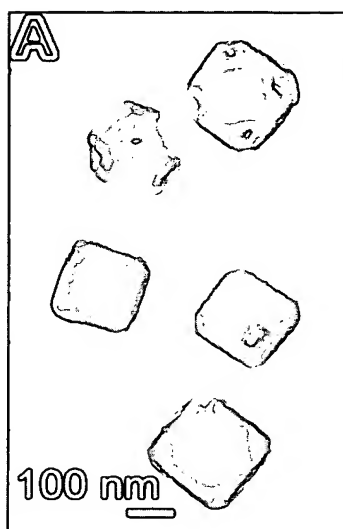


Fig. 6A

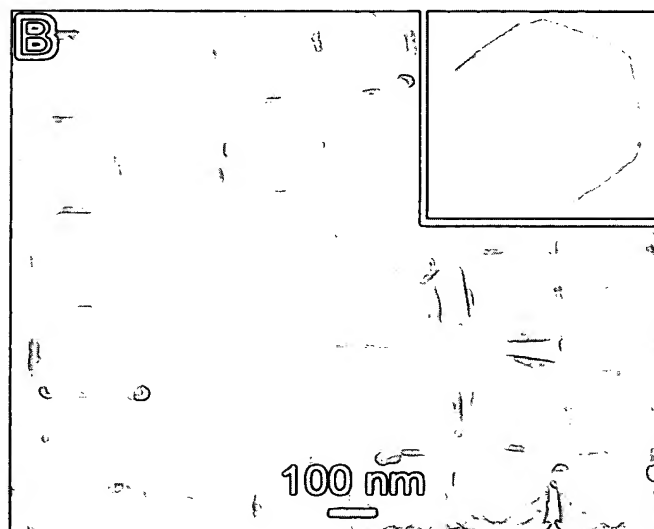


Fig. 6B

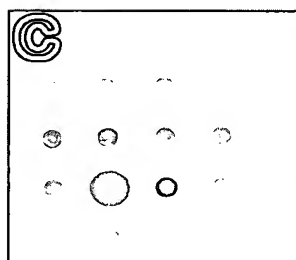


Fig. 6C

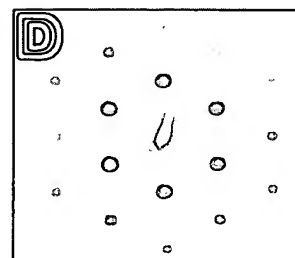


Fig. 6D

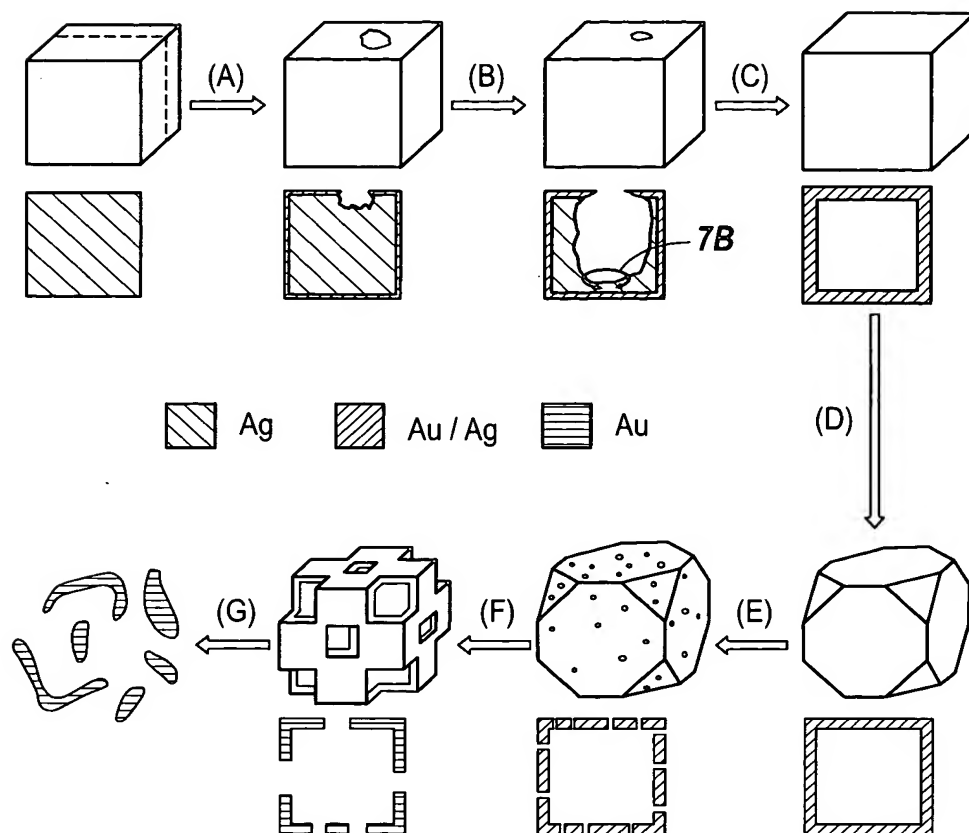


Fig. 7A

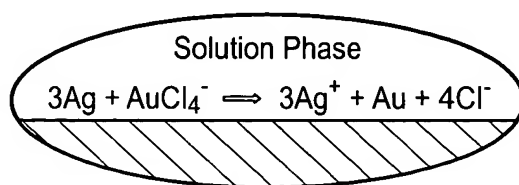


Fig. 7B

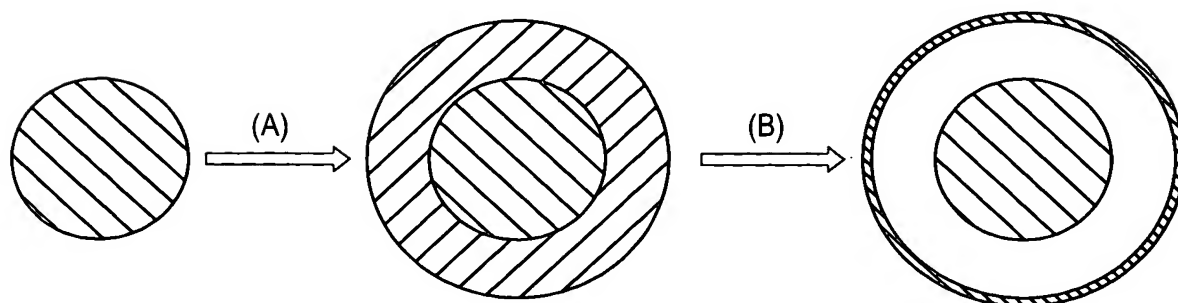


Fig. 8

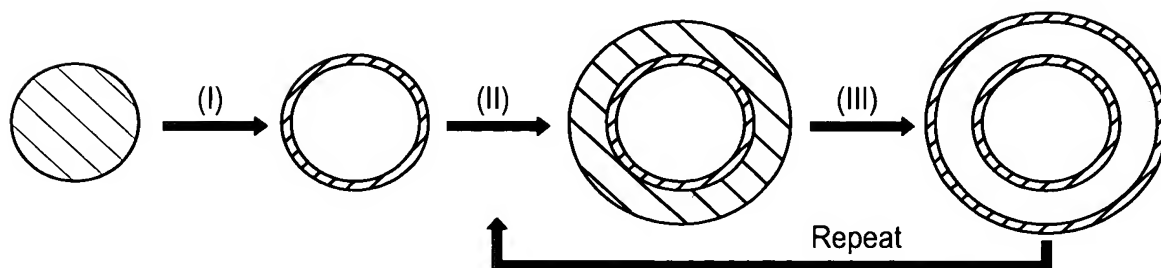


Fig. 9A

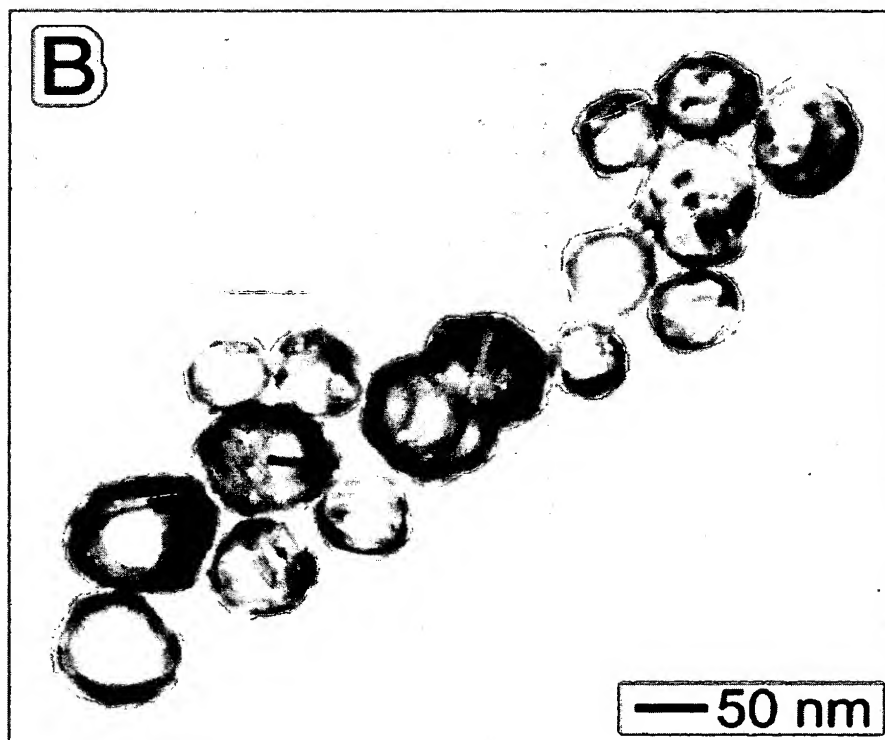


Fig. 9B

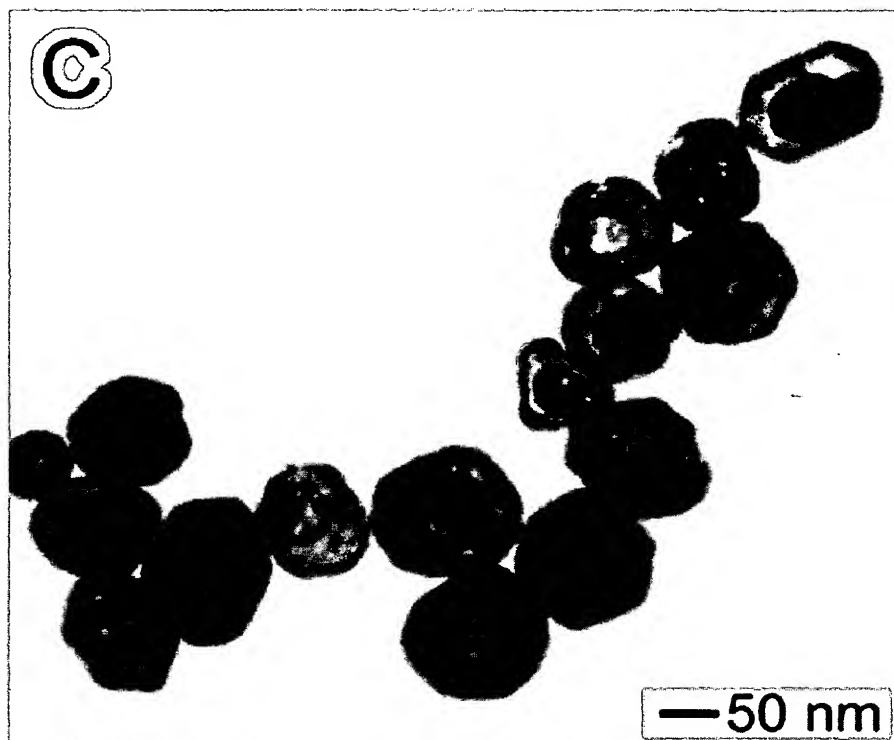


Fig. 9C



Fig. 9D

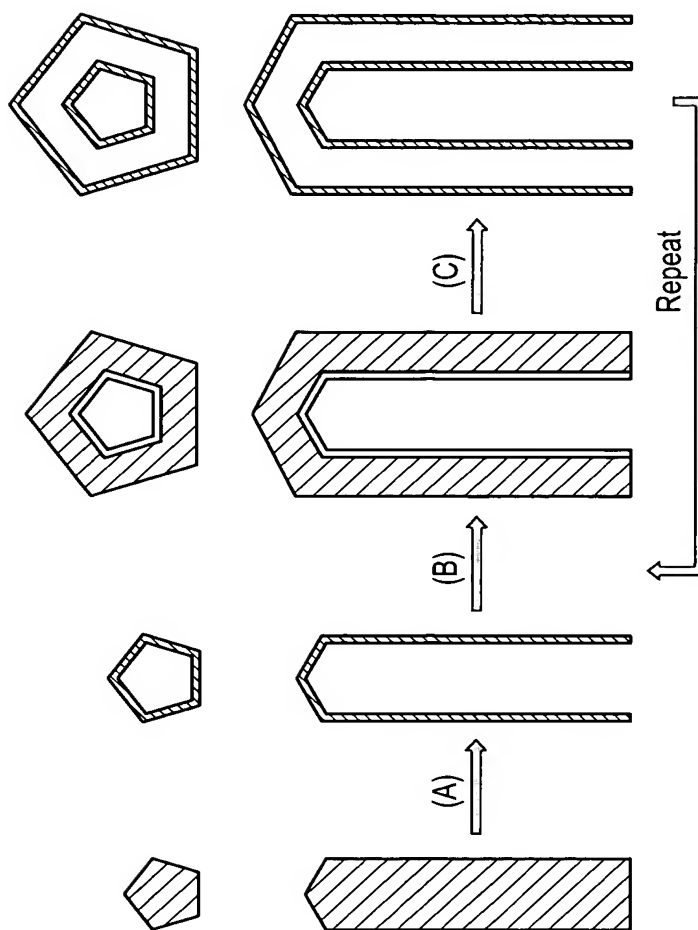
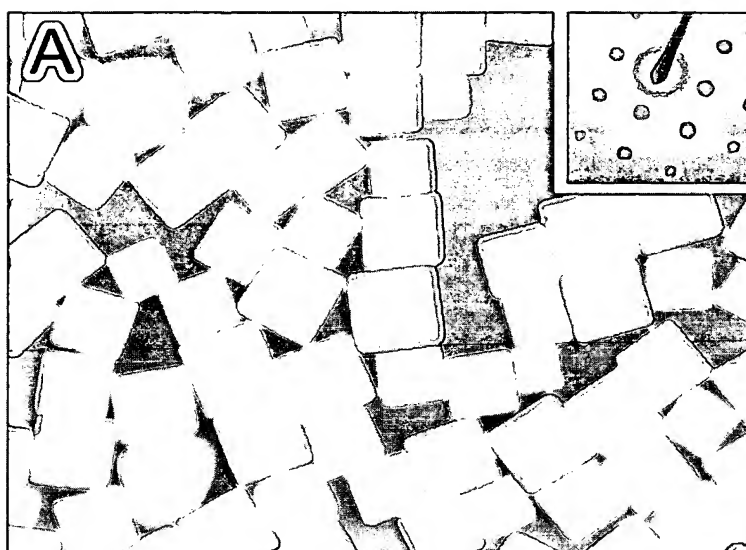
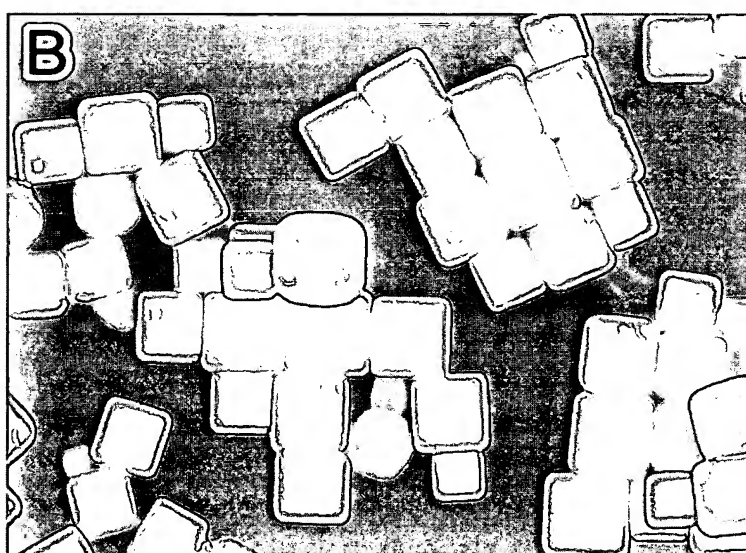


Fig. 10



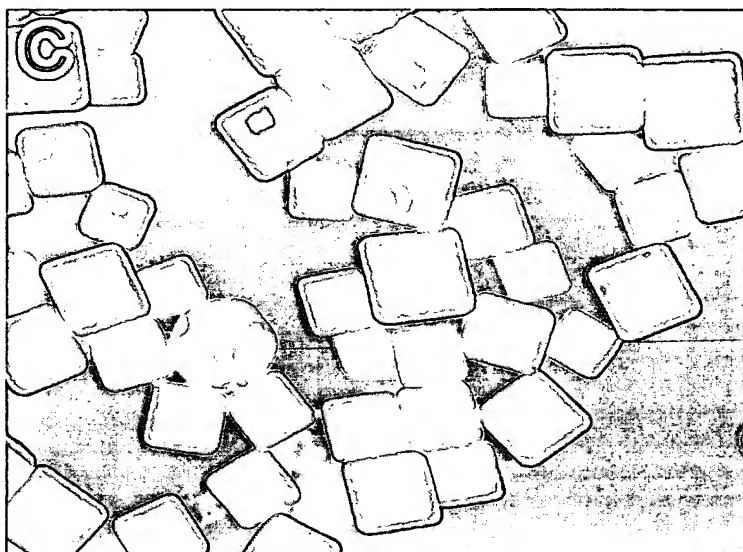
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Fig. 11A



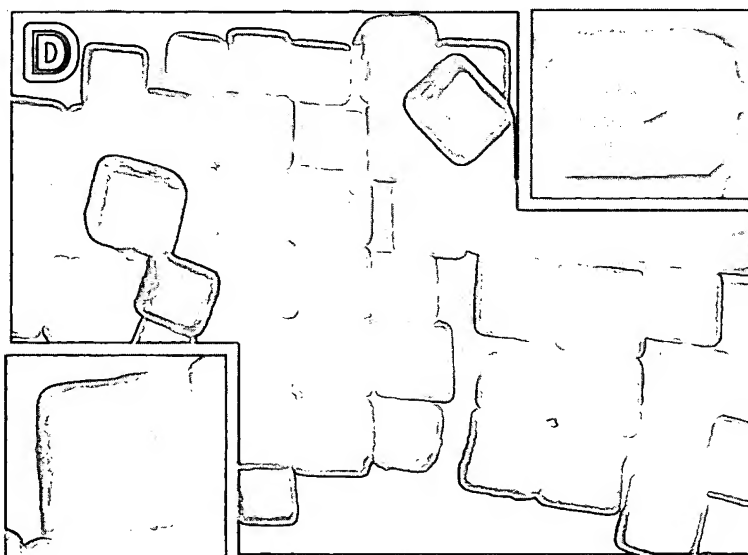
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Fig. 11B



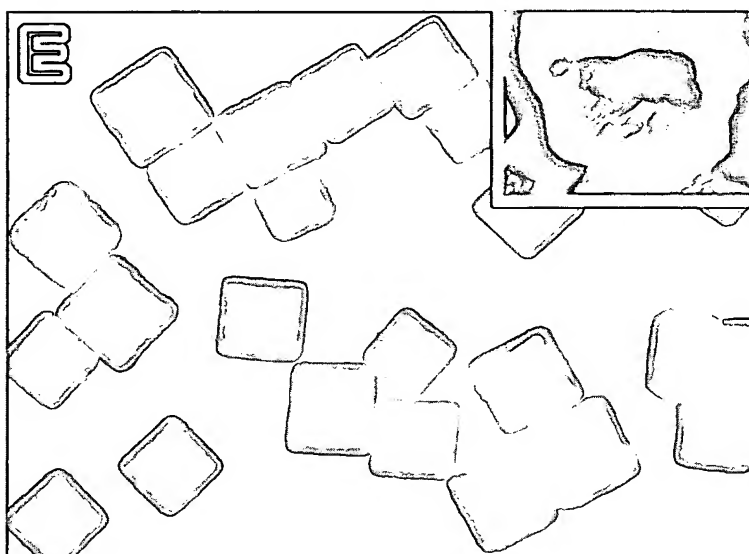
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Fig. 11C



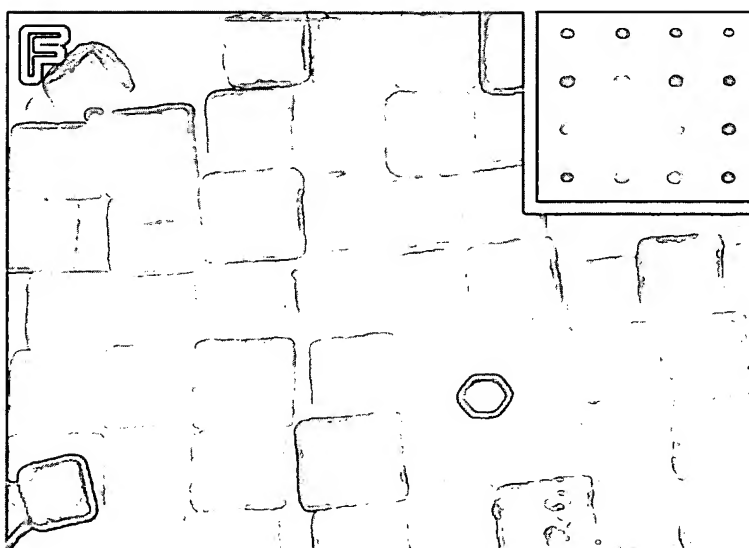
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Fig. 11D



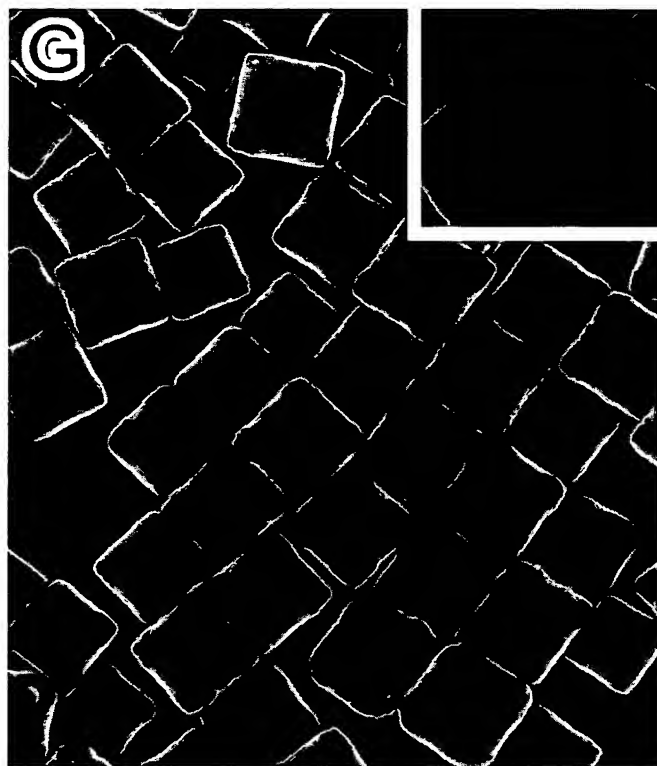
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Fig. 11E



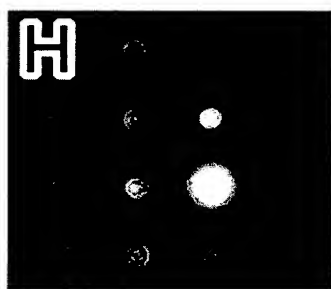
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Fig. 11F



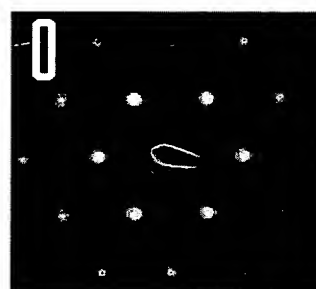
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Fig. 11G



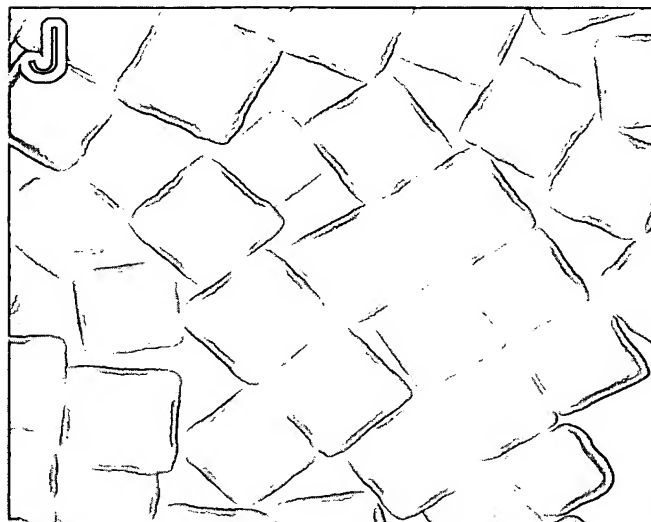
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Fig. 11H



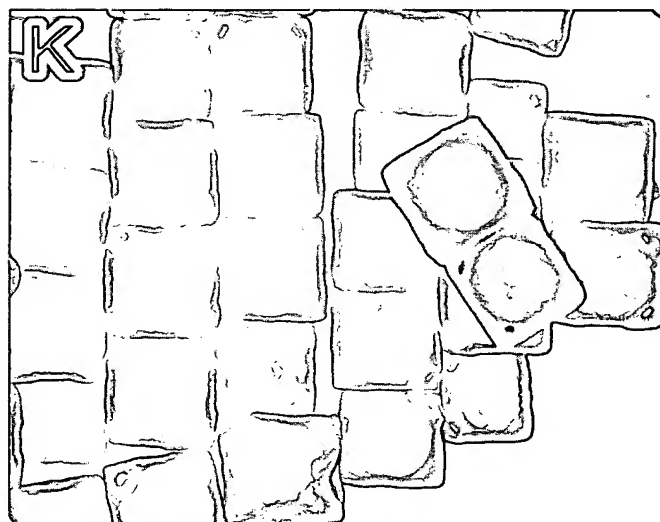
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Fig. 11I



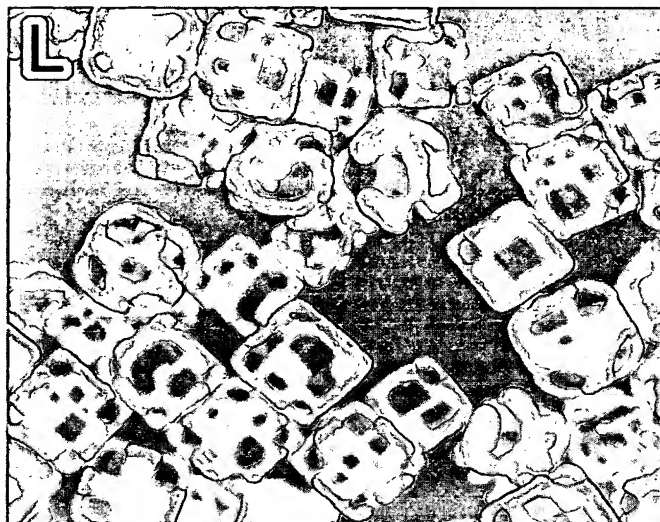
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Fig. 11J



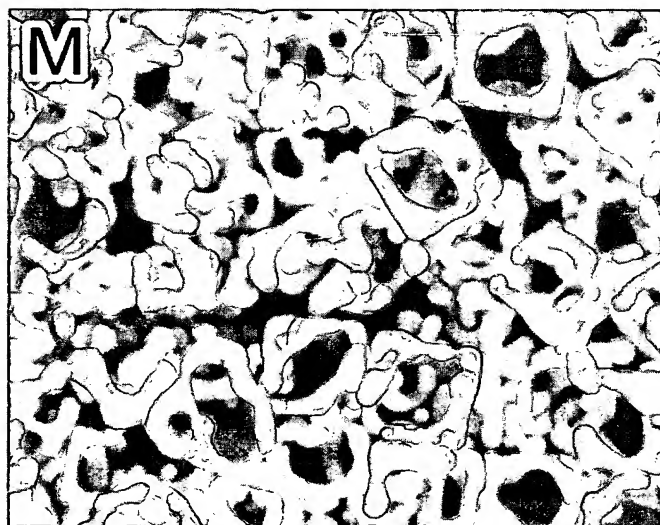
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Fig. 11K



—100 nm

Fig. 11L



—100 nm

Fig. 11M

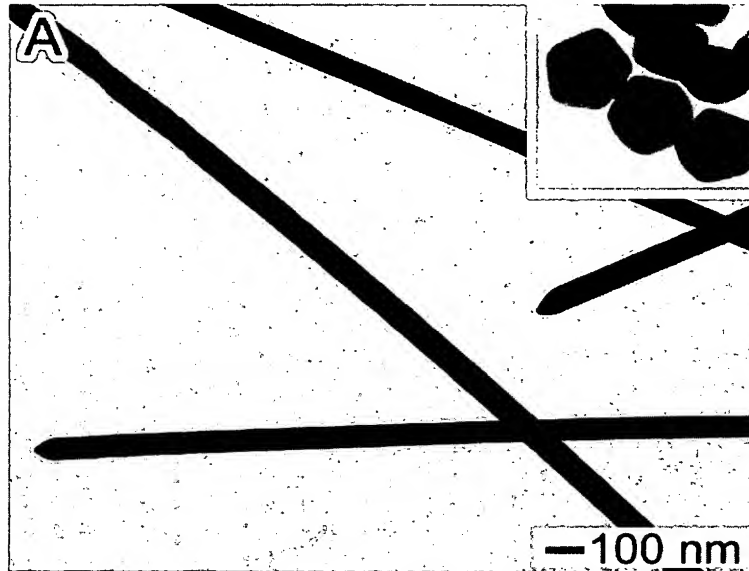


Fig. 12A

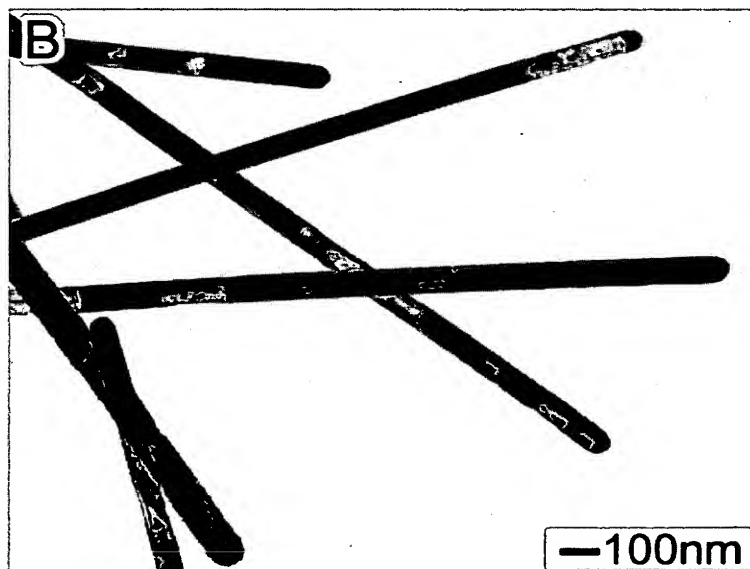


Fig. 12B

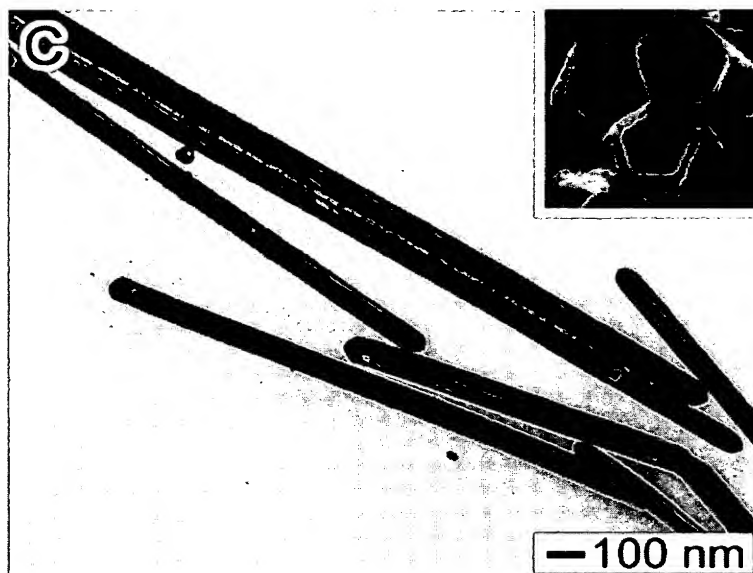


Fig. 12C

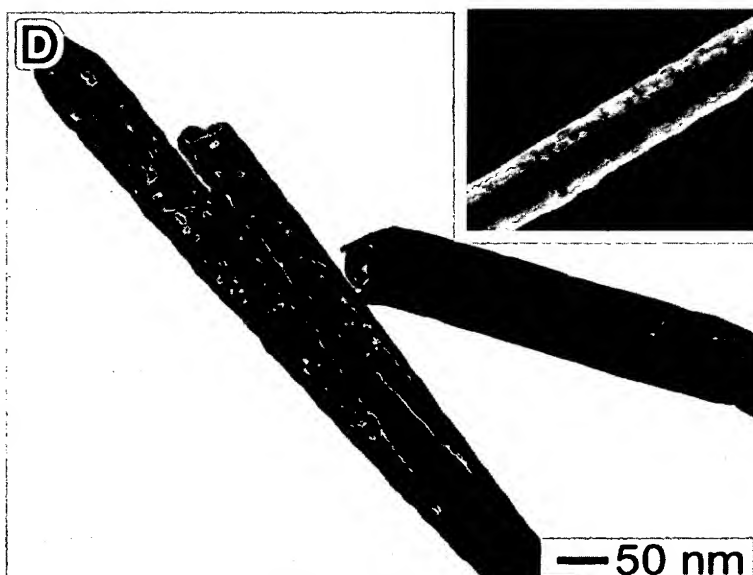


Fig. 12D

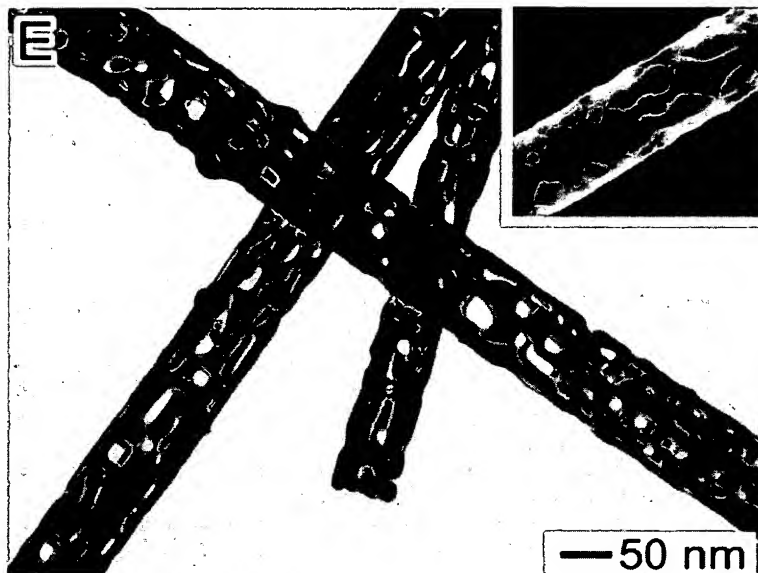


Fig. 12E

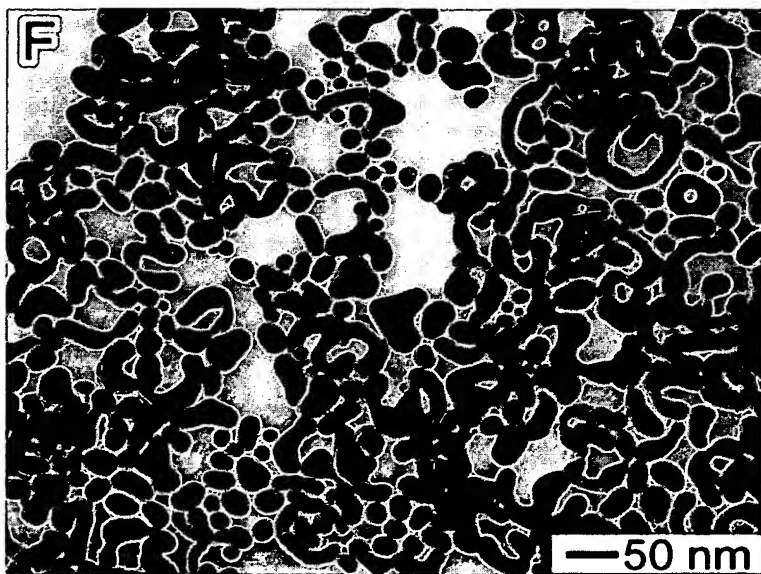
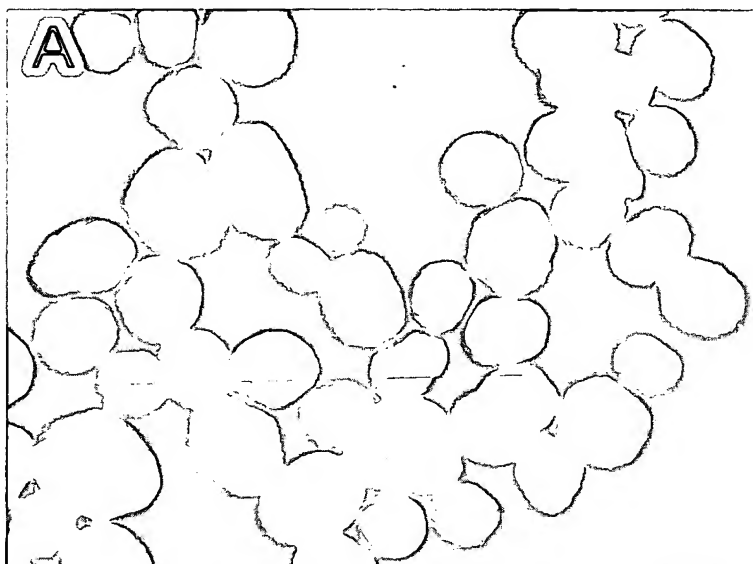
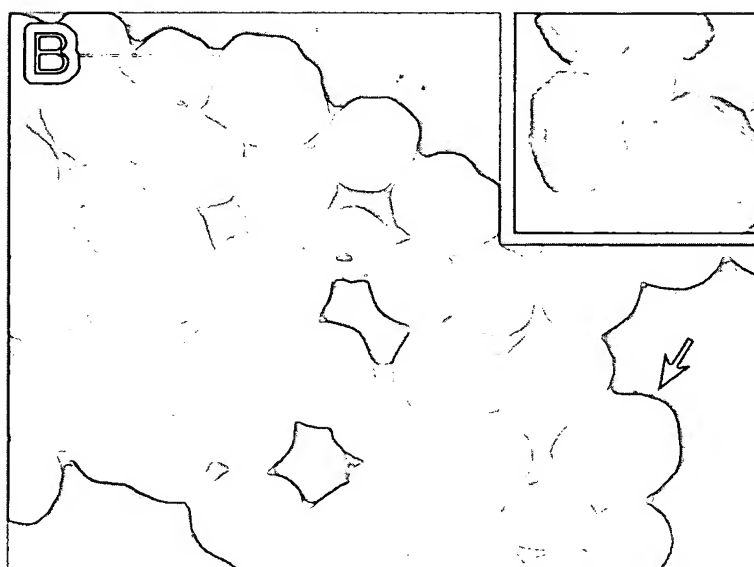


Fig. 12F



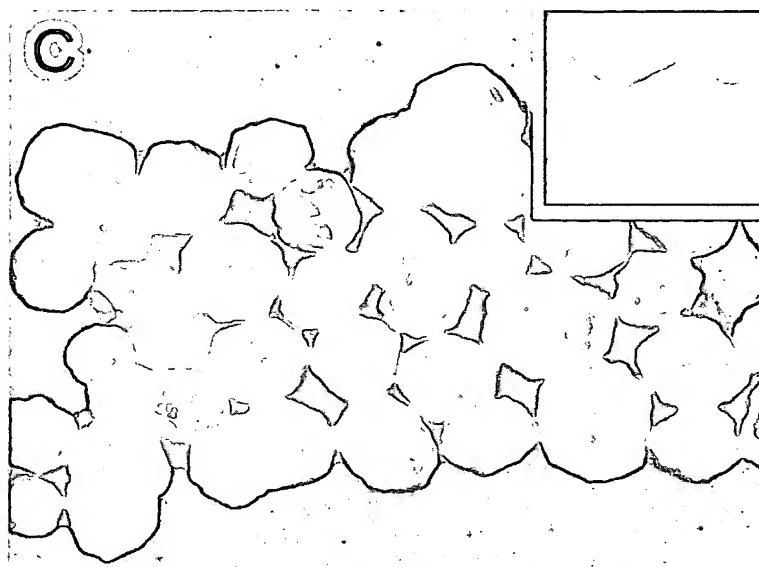
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Fig. 13A



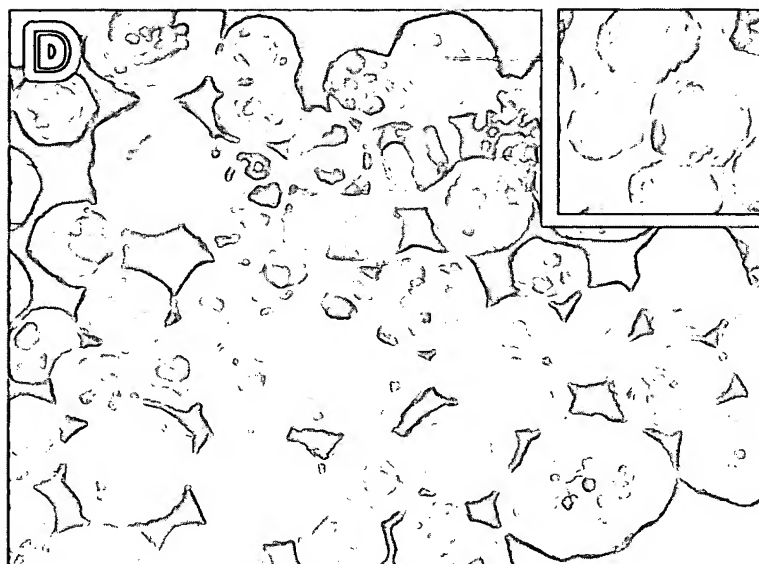
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Fig. 13B



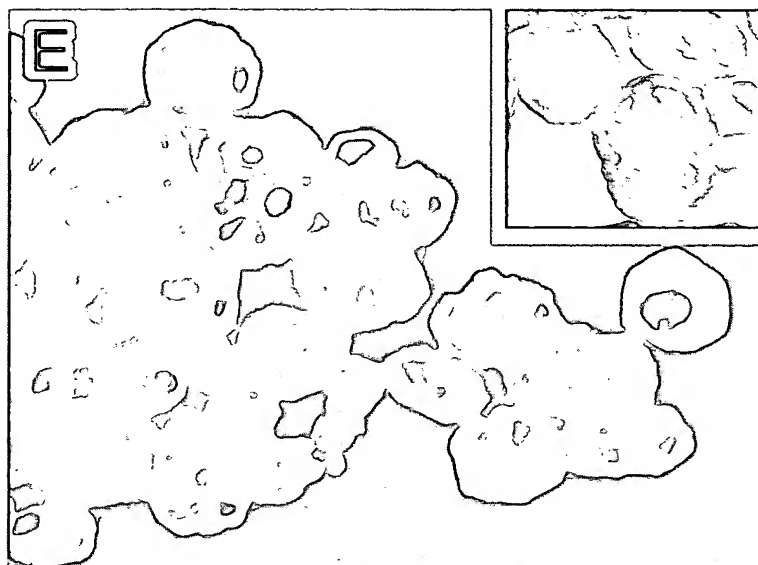
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Fig. 13C



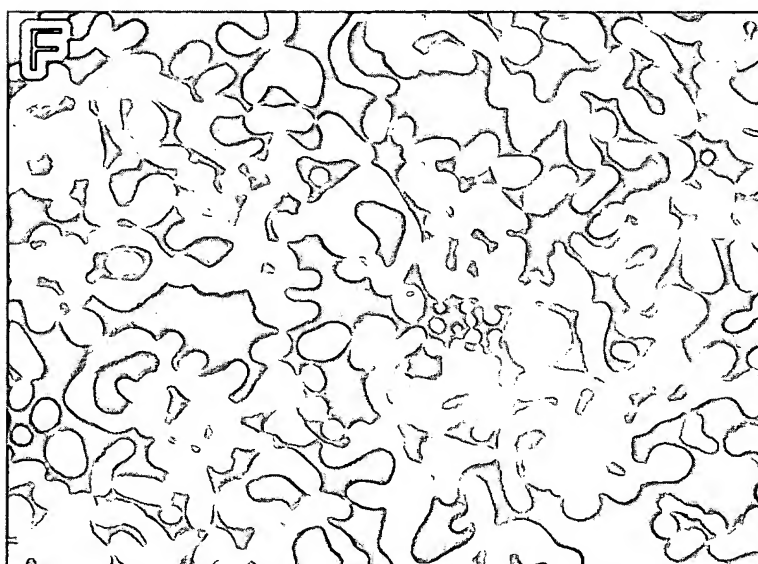
— 50 nm

Fig. 13D



— 50 nm

Fig. 13E



— 50 nm

Fig. 13F

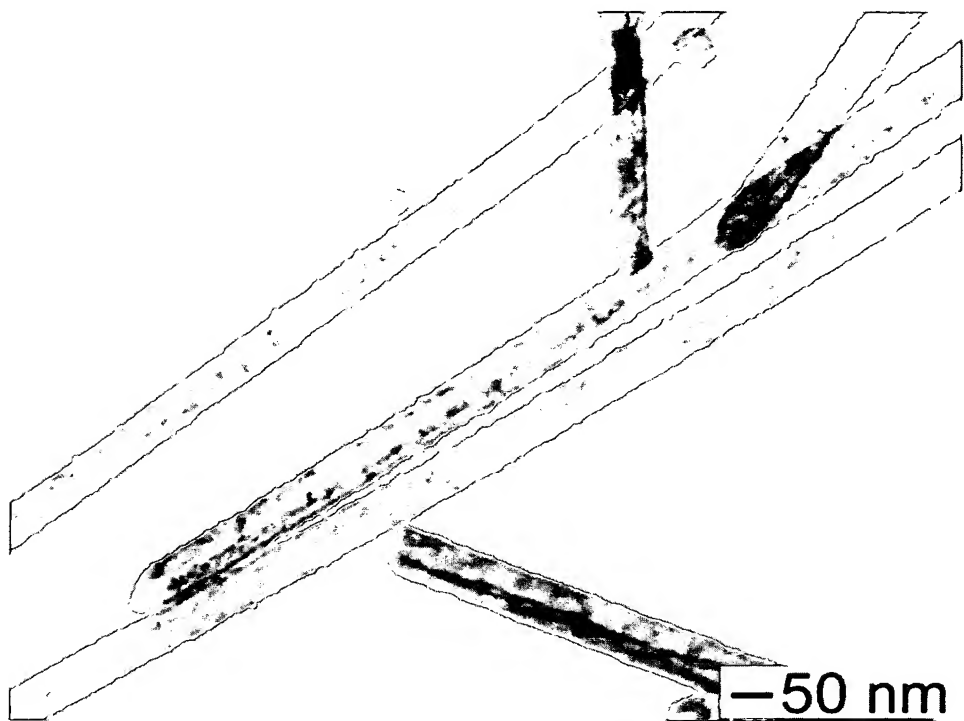


Fig. 14

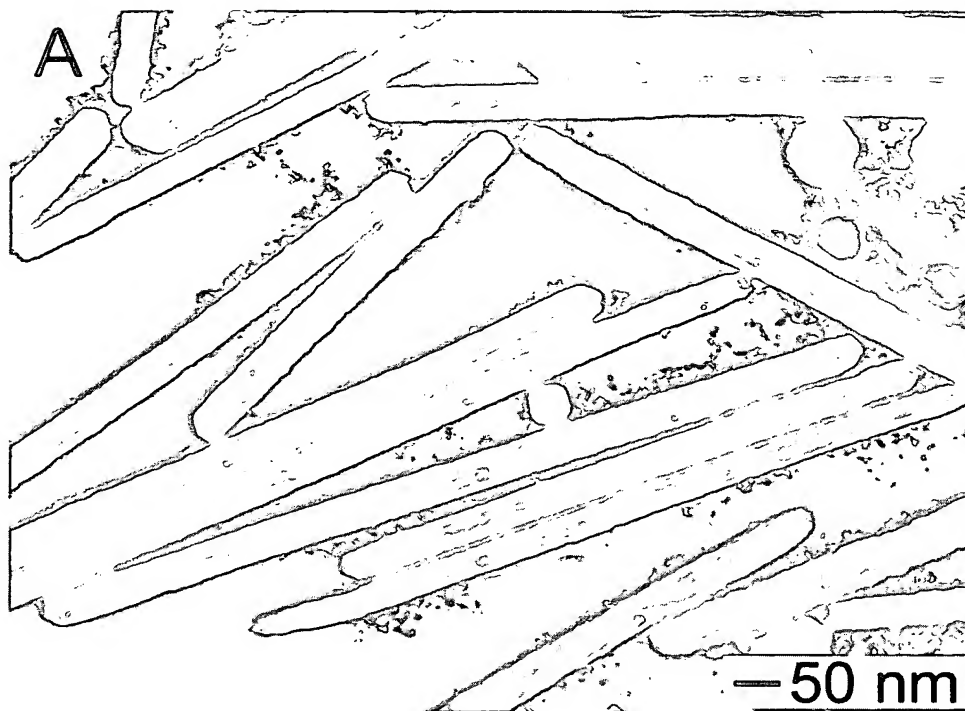


Fig. 15A

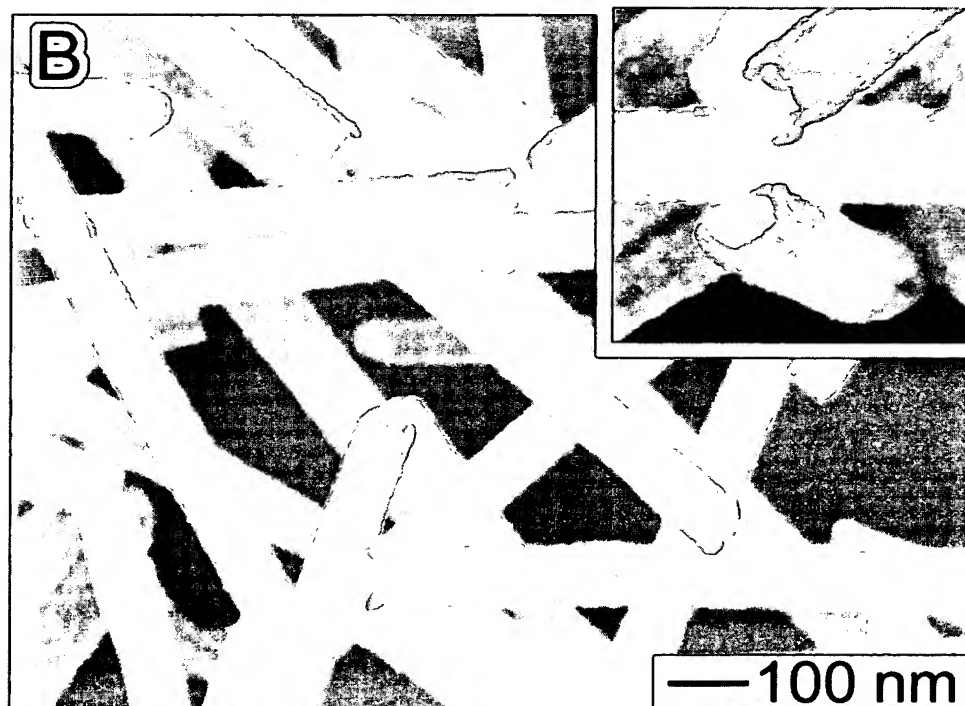


Fig. 15B

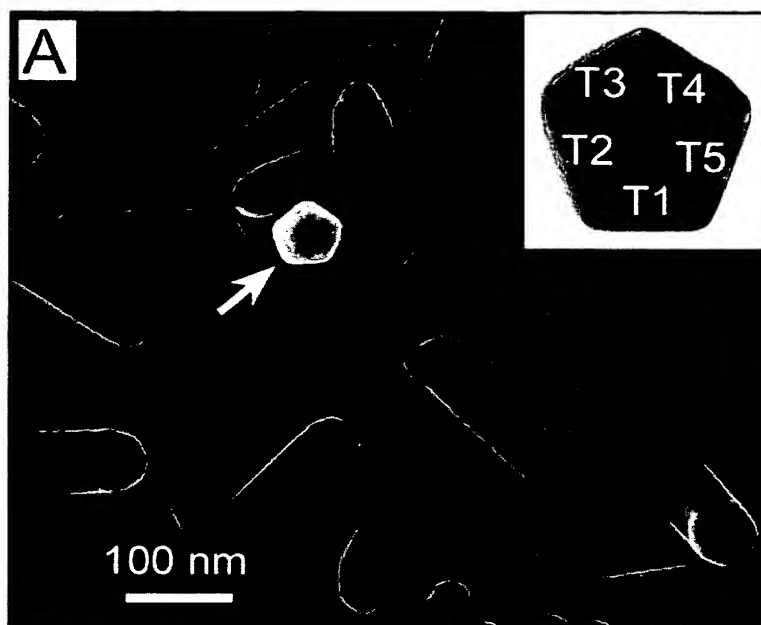


Fig. 16A

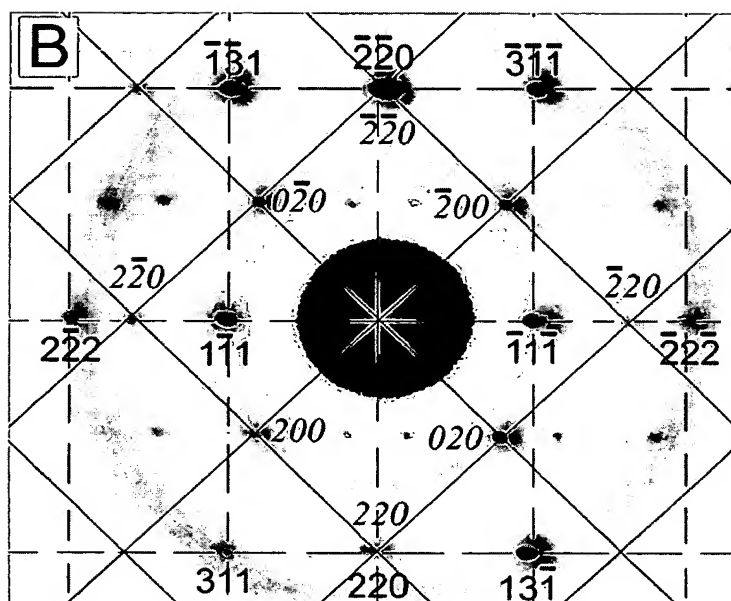


Fig. 16B

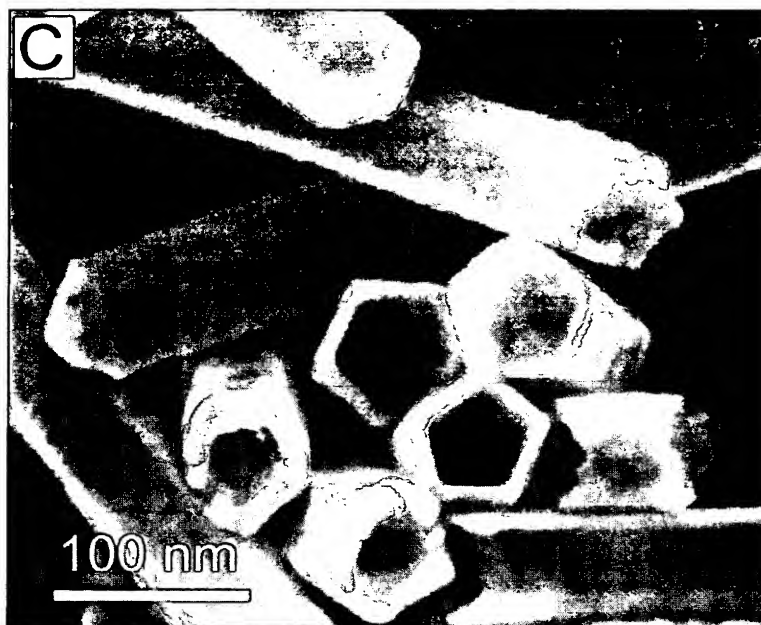


Fig. 16C

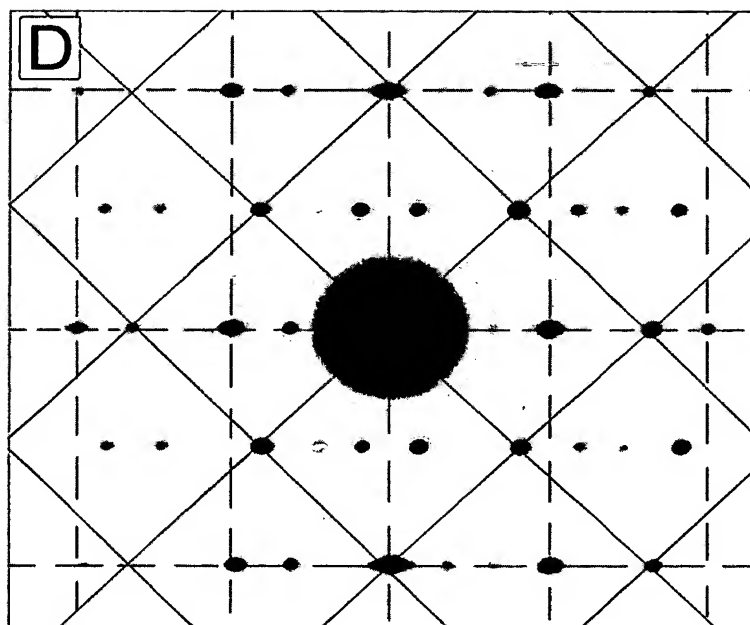


Fig. 16D

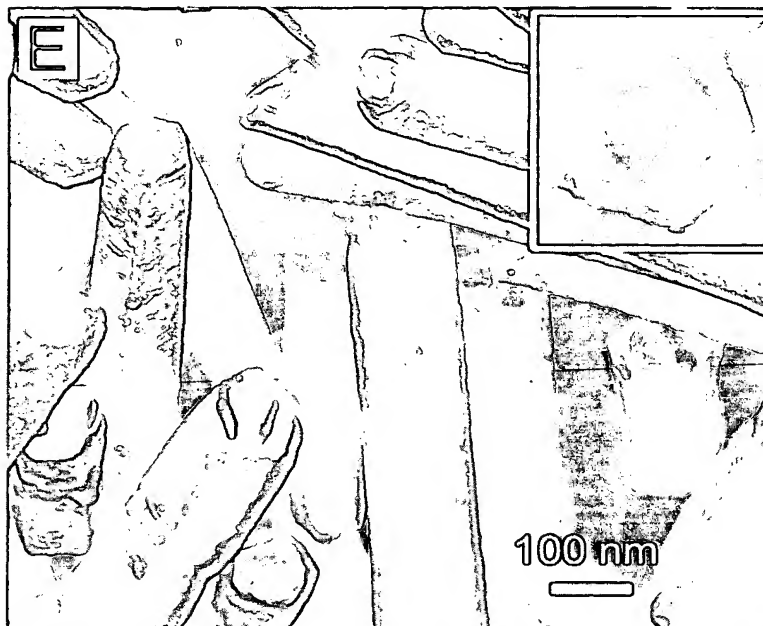


Fig. 16E

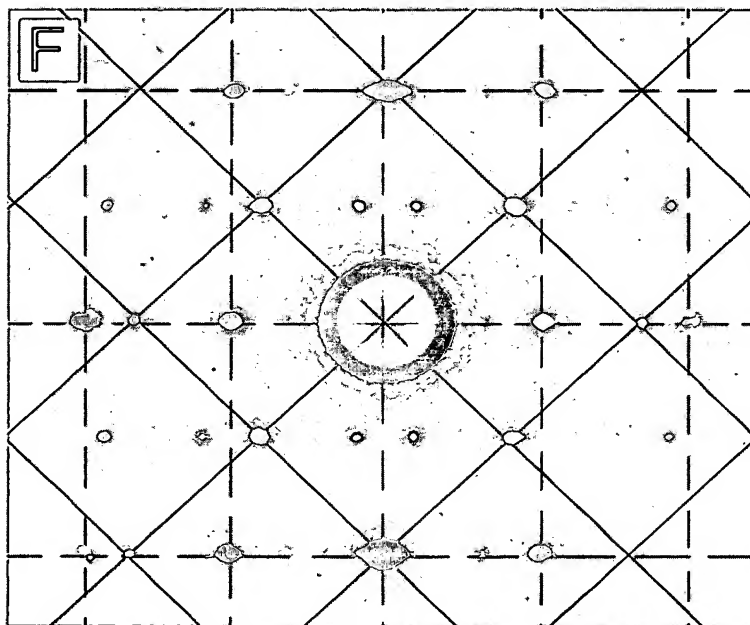


Fig. 16F

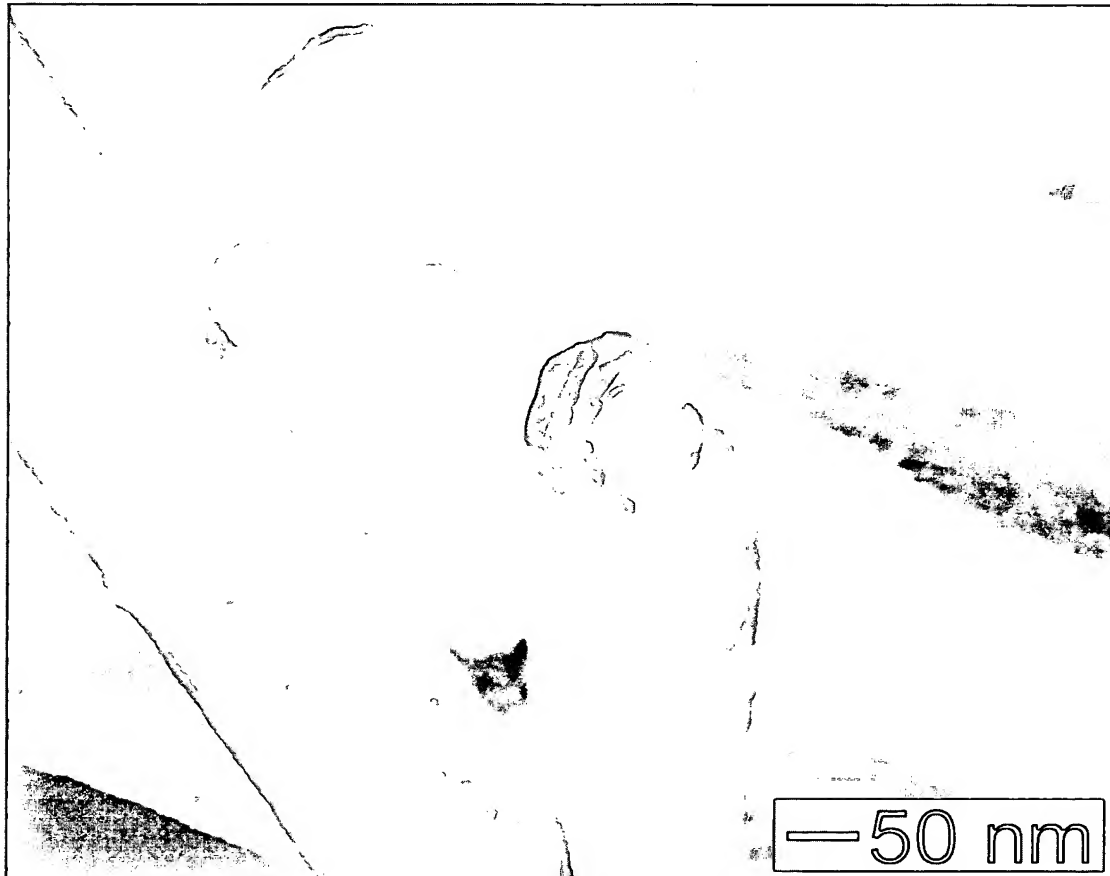


Fig. 17

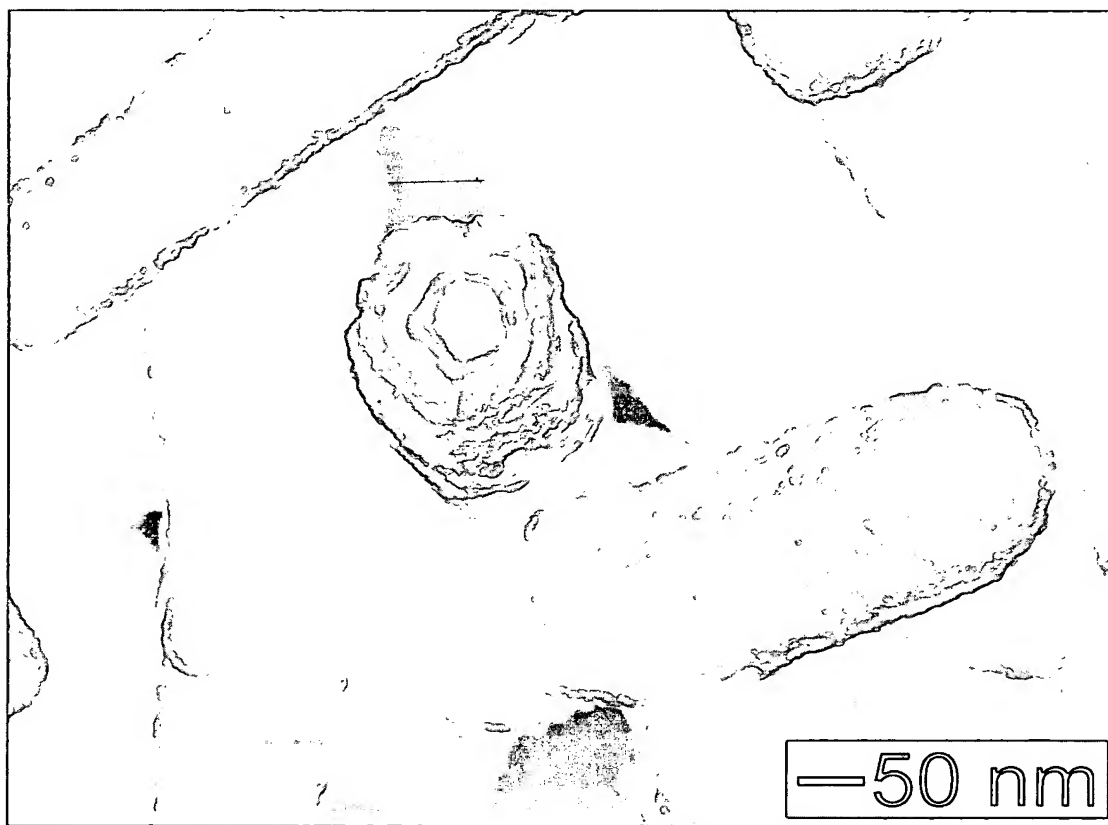


Fig. 18



Title: METHODS OF NANOSTRUCTURE FORMATION AND SHAPE SELECTION

Inventors: Younan Xia and Yugan Sun

Docket No.: 53433/2 Serial No.: 10/732,910 Filed: 12/09/2003

REPLACEMENT SHEET (Set B)

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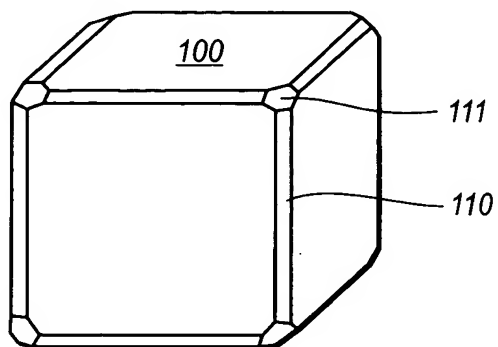


Fig. 1

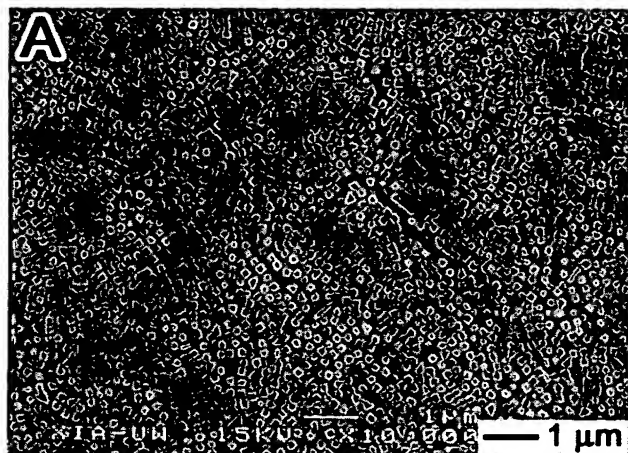


Fig. 2A

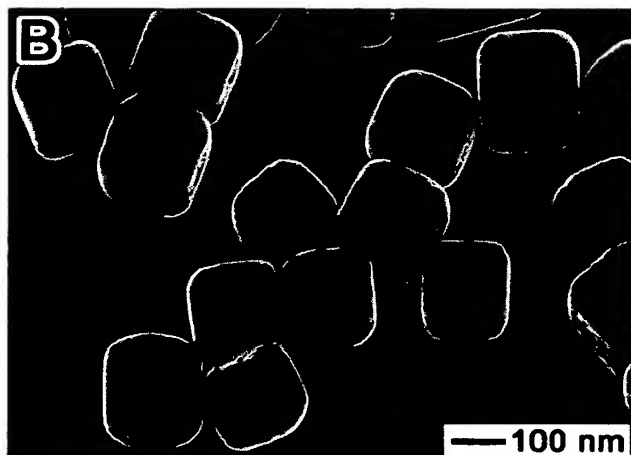


Fig. 2B

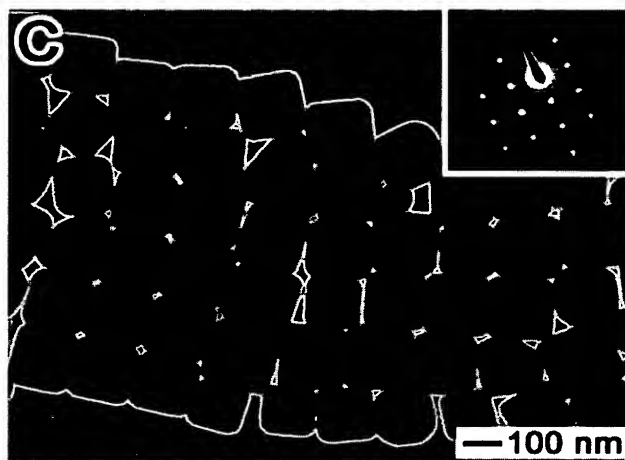


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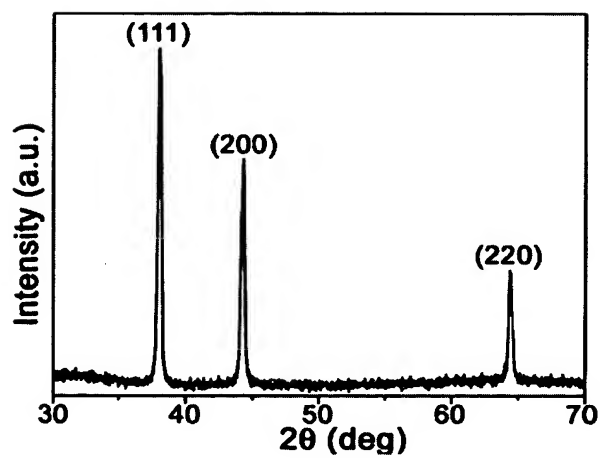


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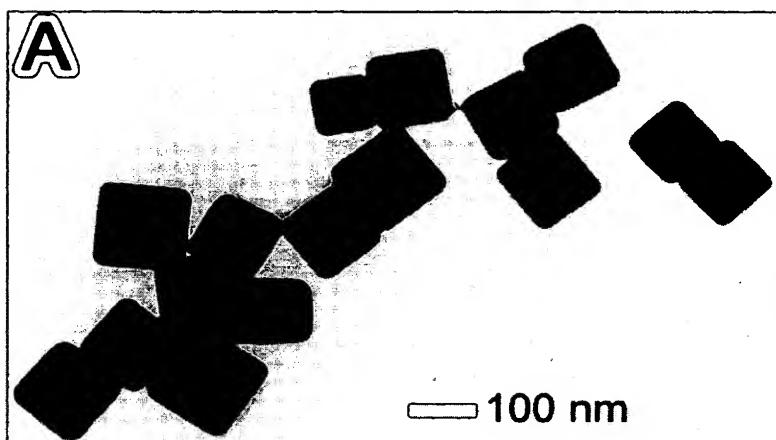


Fig. 3A

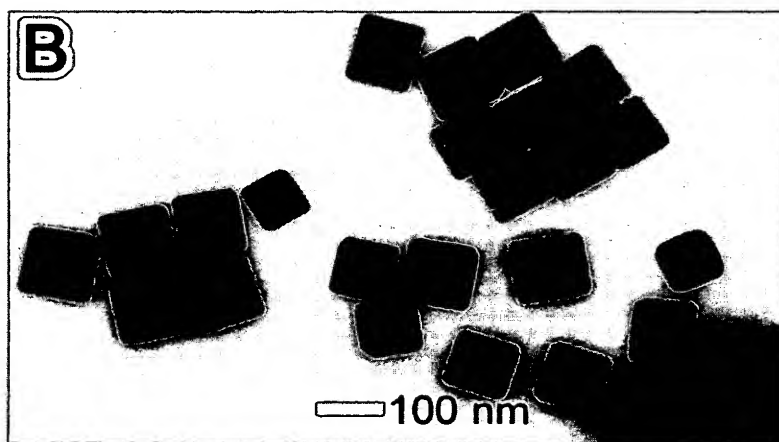


Fig. 3B

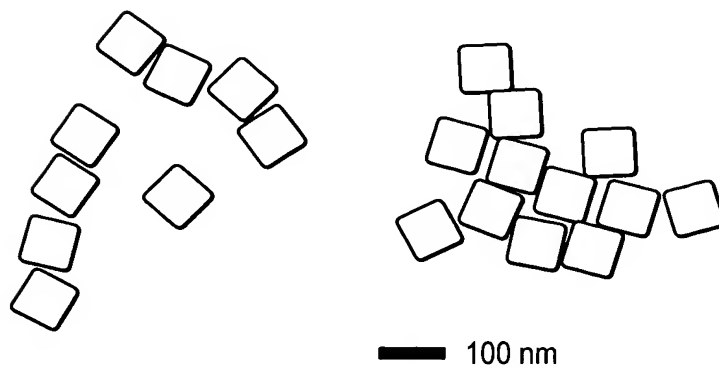


Fig. 4

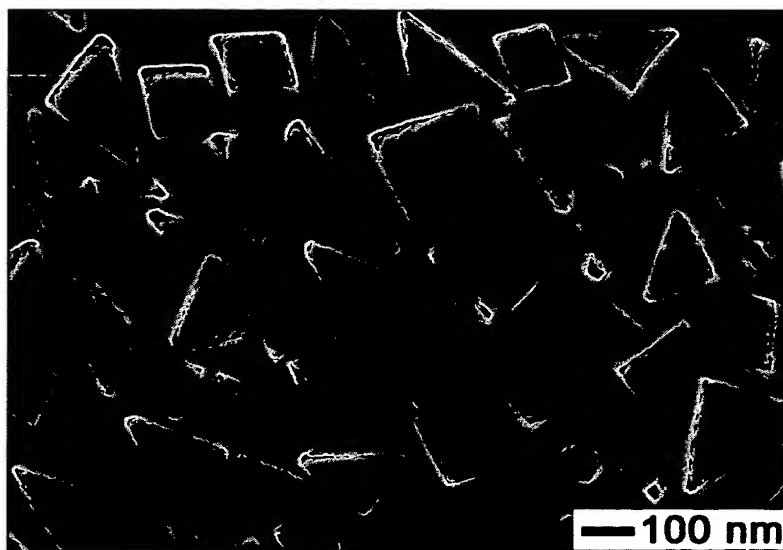


Fig. 5

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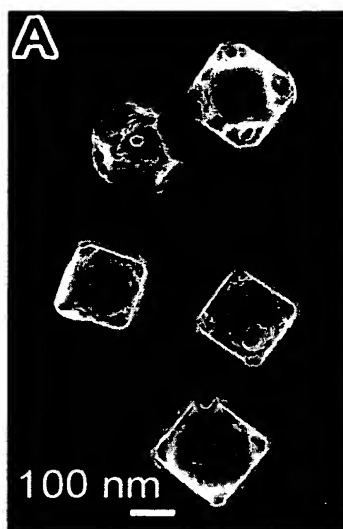


Fig. 6A

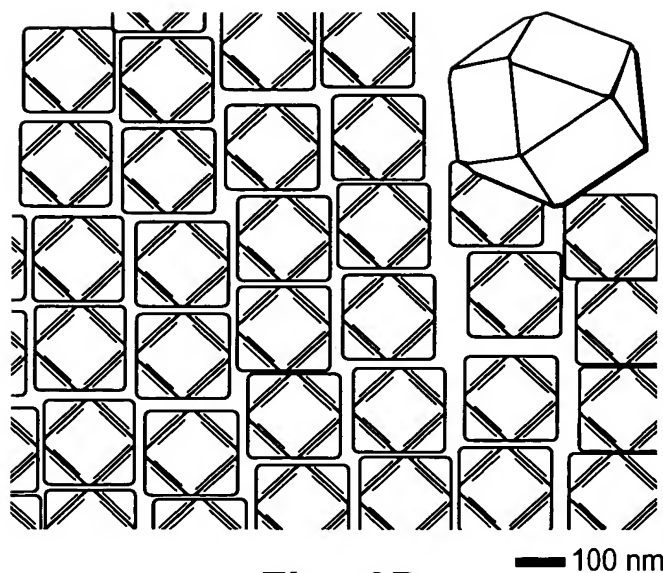


Fig. 6B

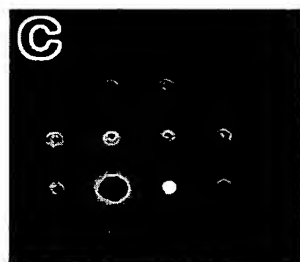


Fig. 6C

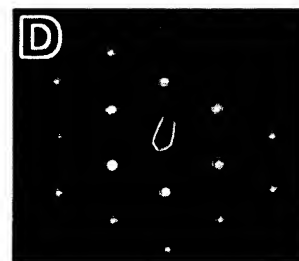


Fig. 6D

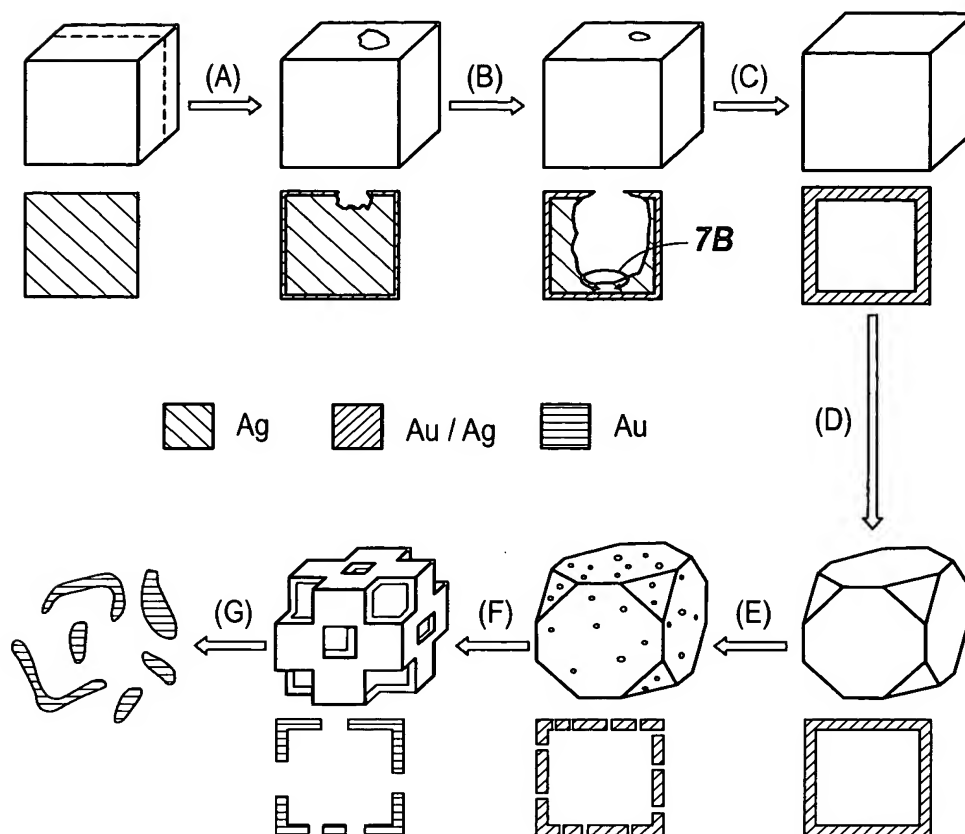


Fig. 7A

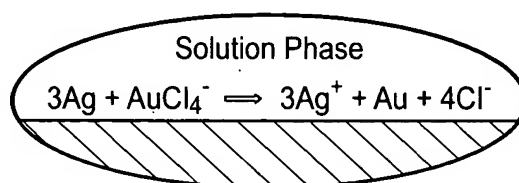


Fig. 7B

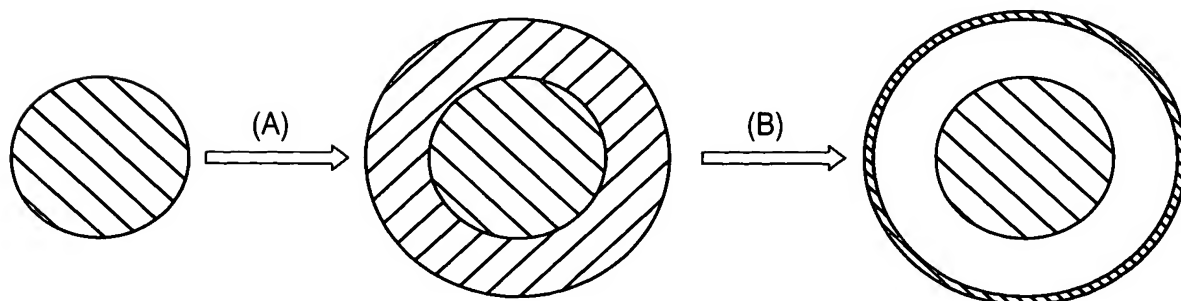


Fig. 8

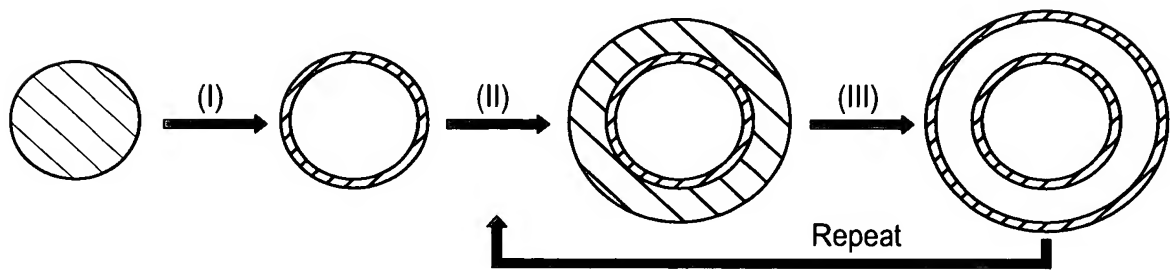


Fig. 9A

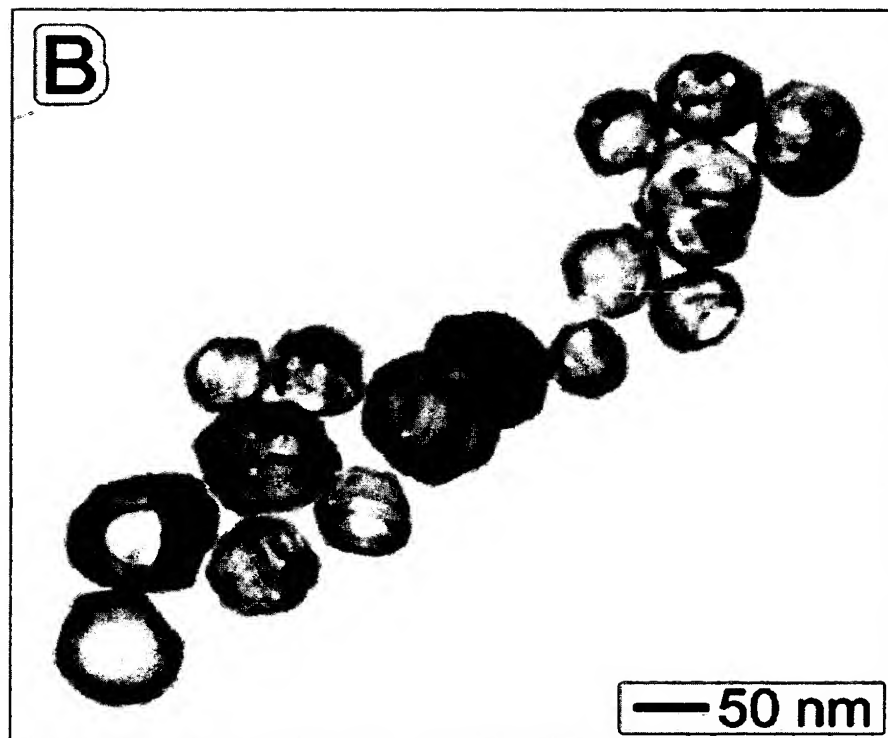


Fig. 9B

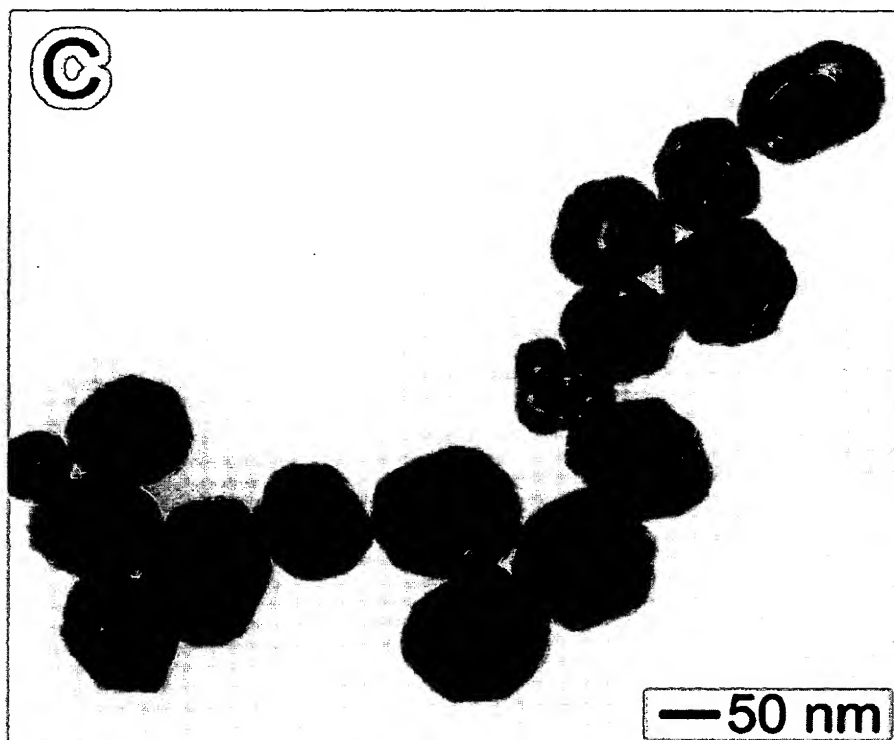


Fig. 9C

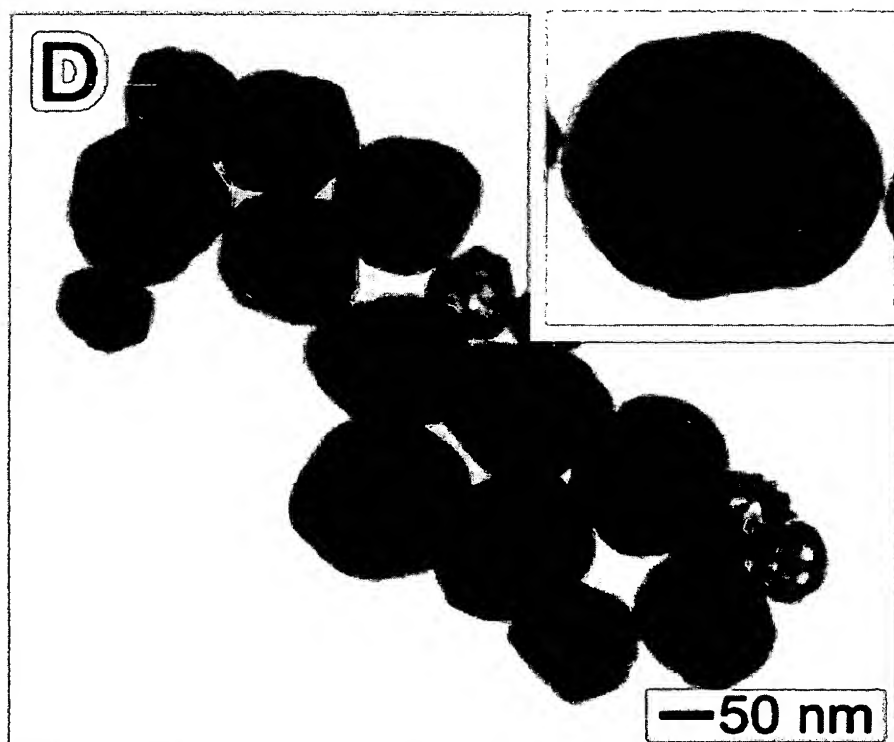


Fig. 9D

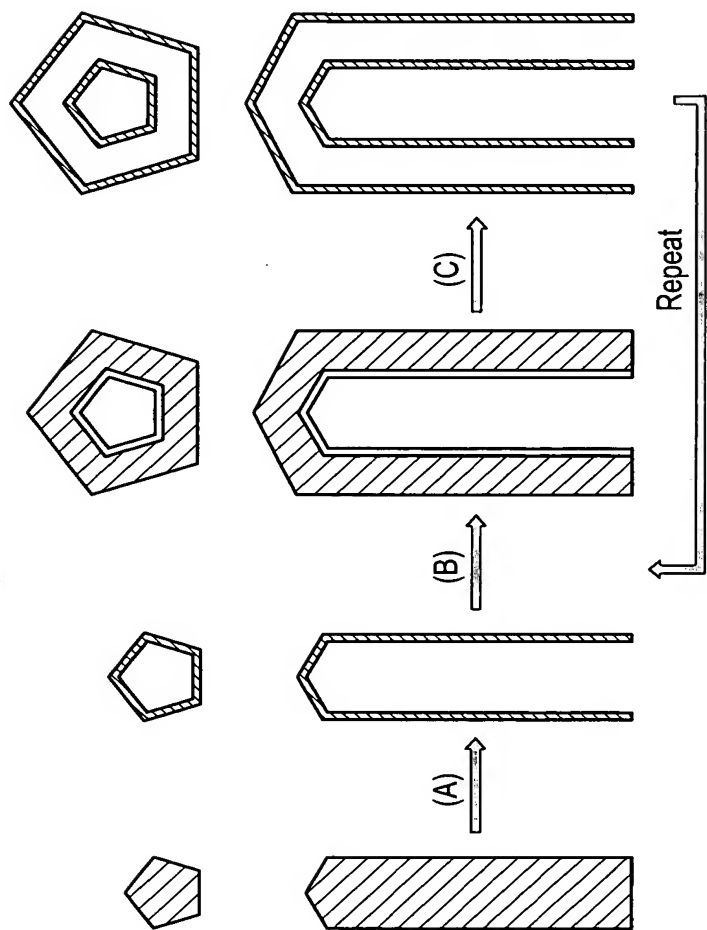


Fig. 10

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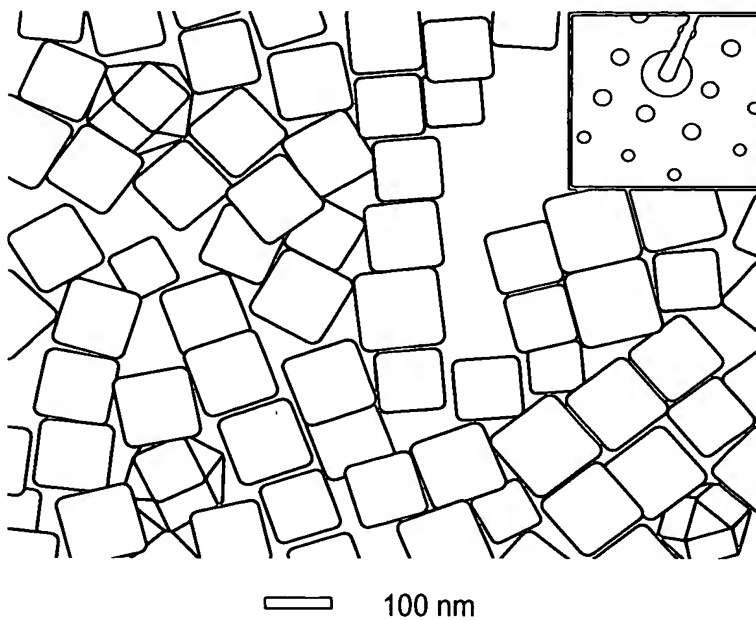


Fig. 11A

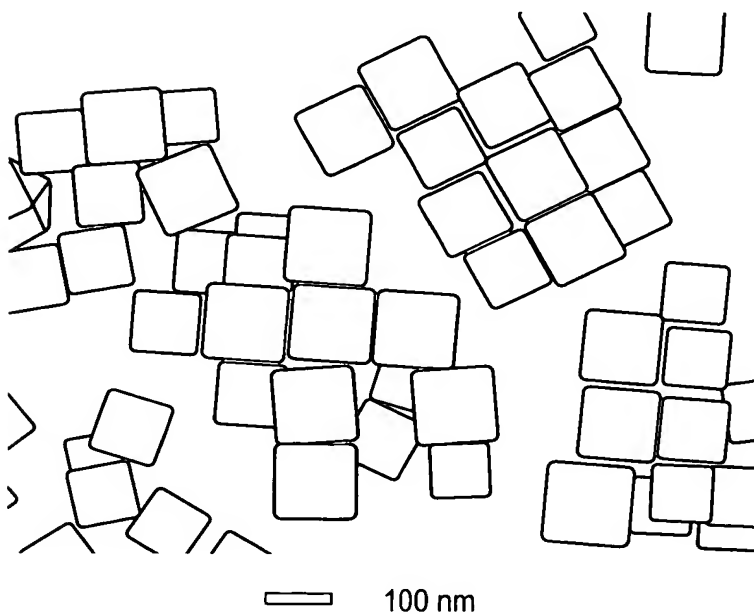


Fig. 11B

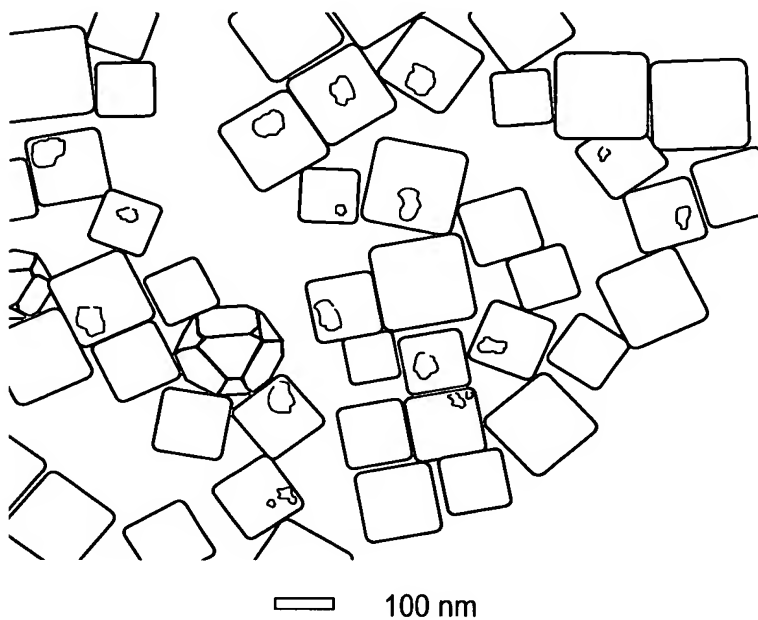


Fig. 11C

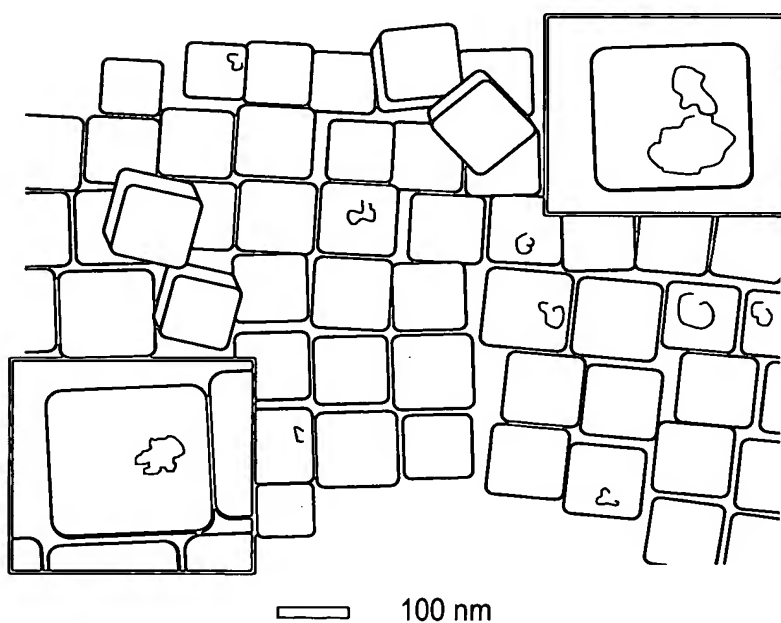


Fig. 11D

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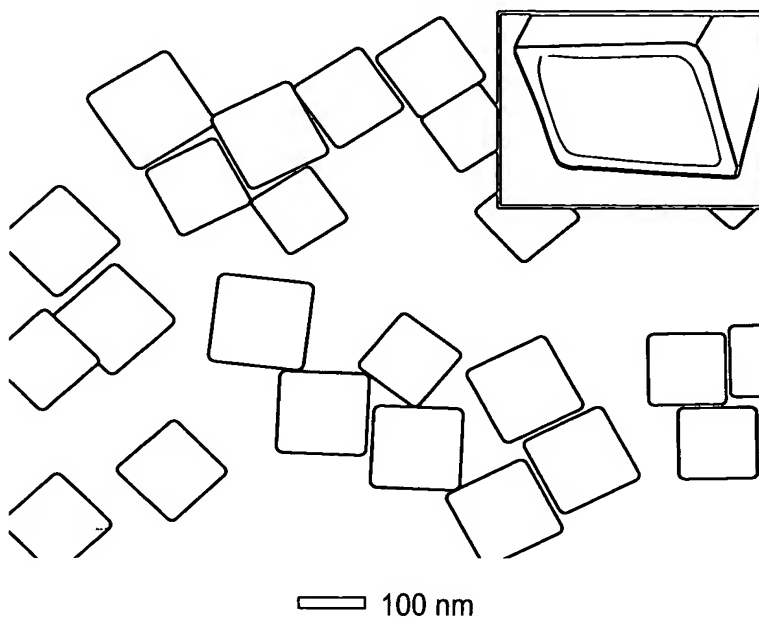


Fig. 11E

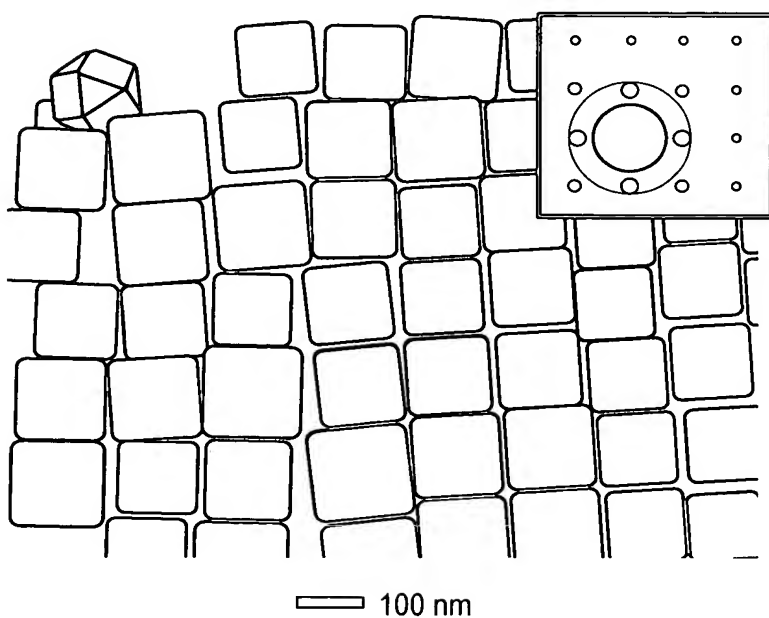
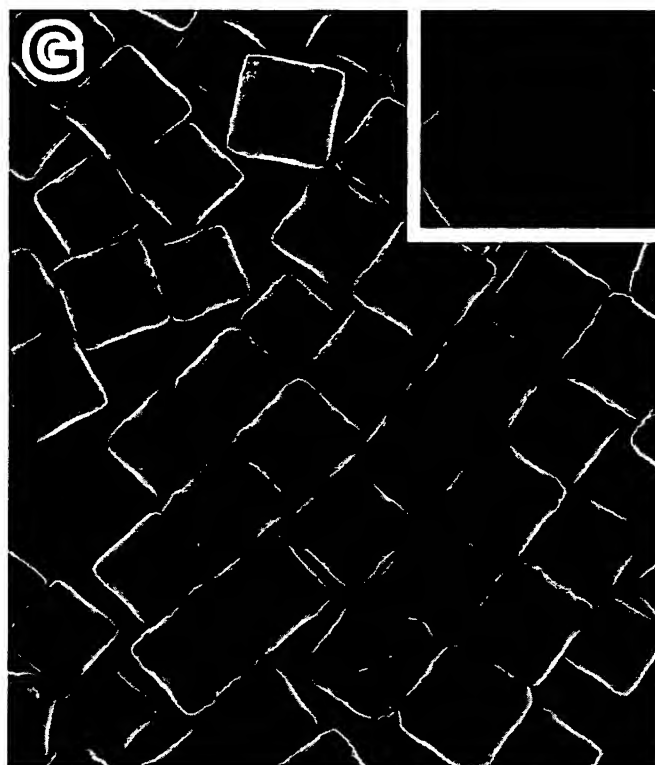
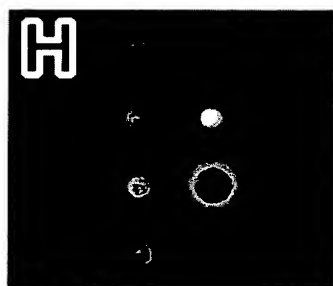


Fig. 11F



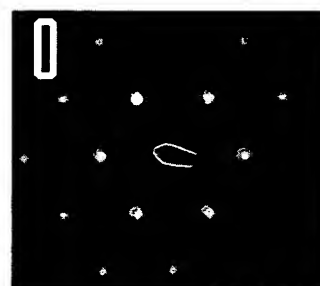
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Fig. 11G



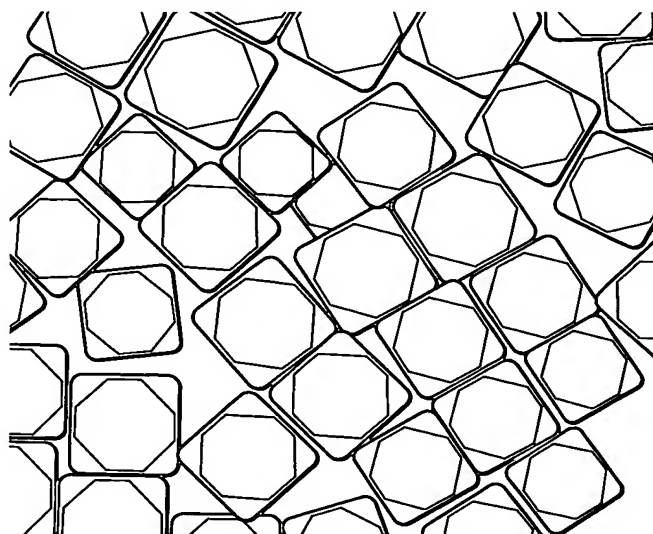
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Fig. 11H



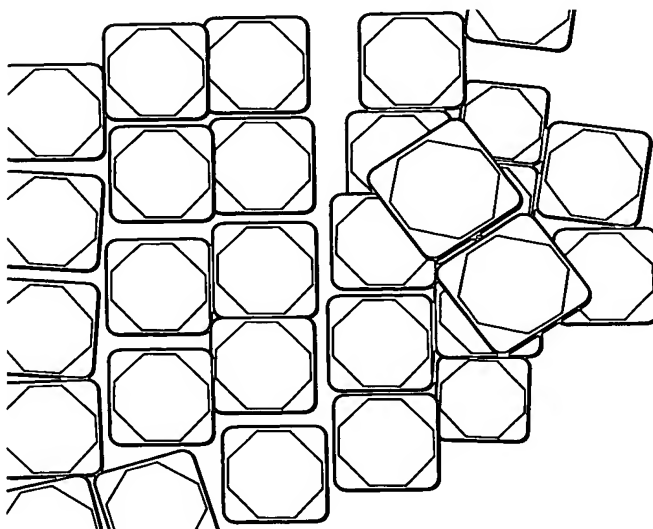
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Fig. 11I



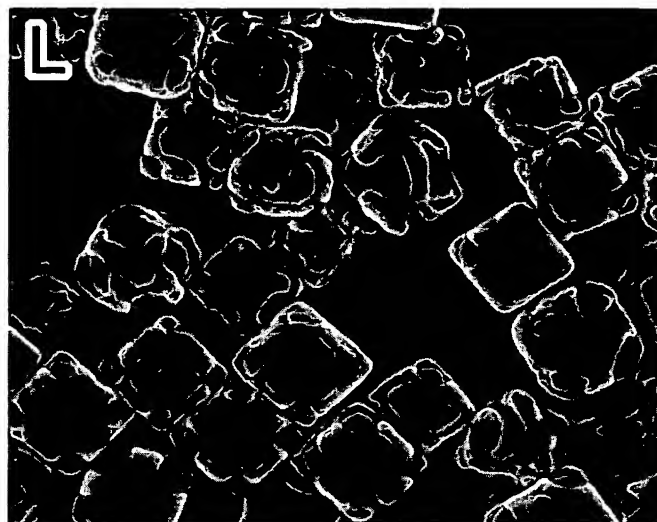
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Fig. 11J



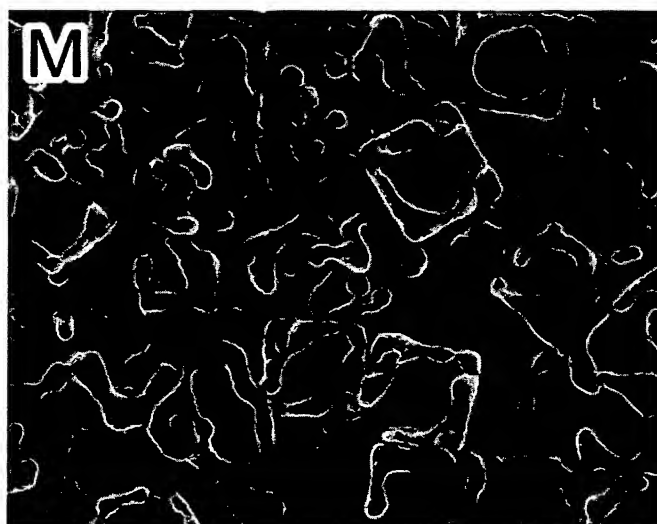
100 nm

Fig. 11K



—100 nm

Fig. 11L



—100 nm

Fig. 11M

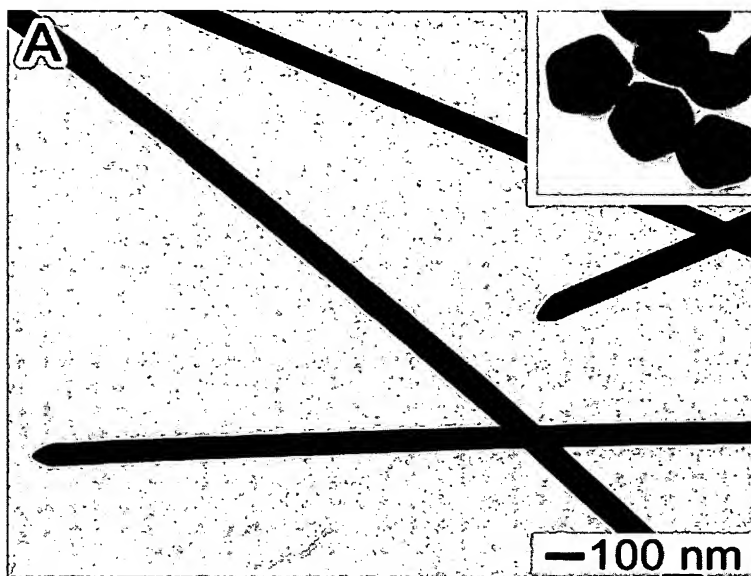


Fig. 12A

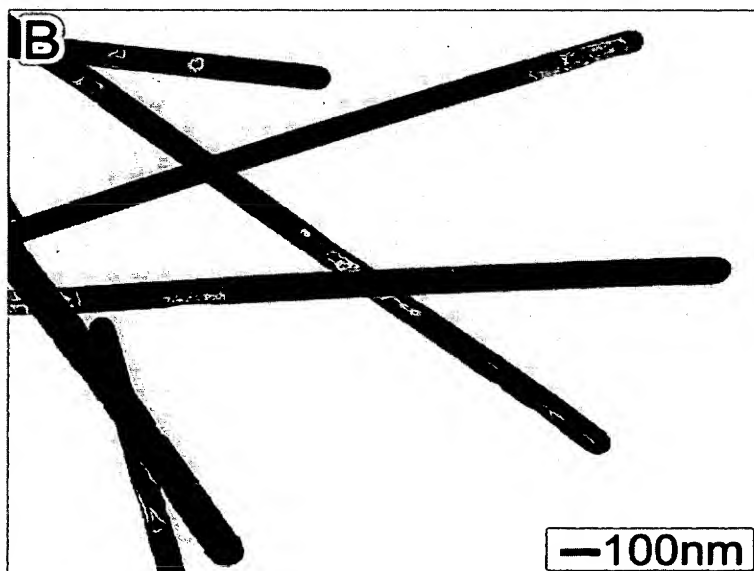


Fig. 12B

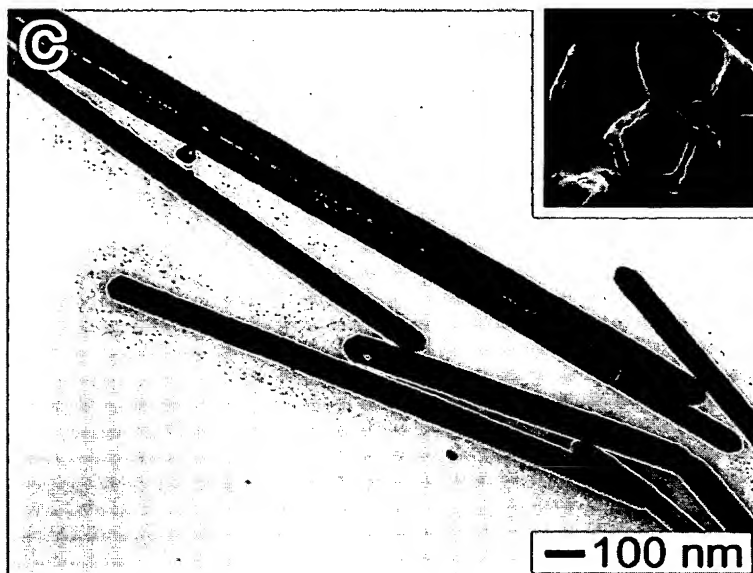


Fig. 12C

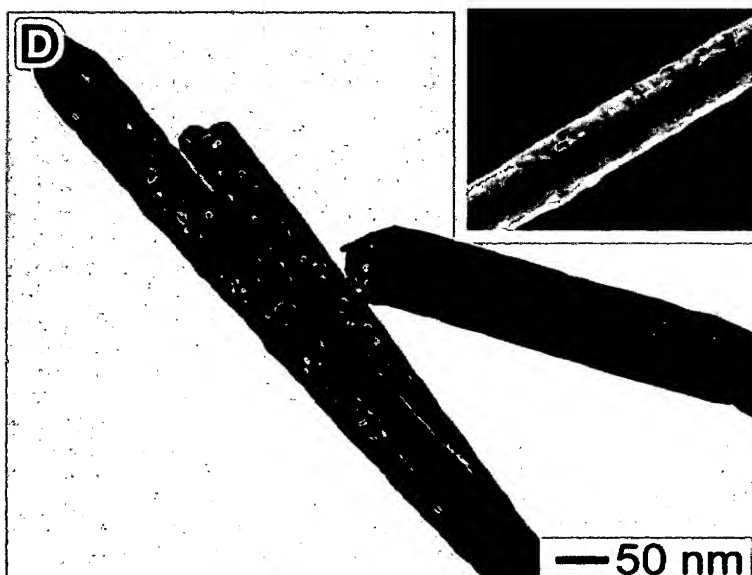


Fig. 12D

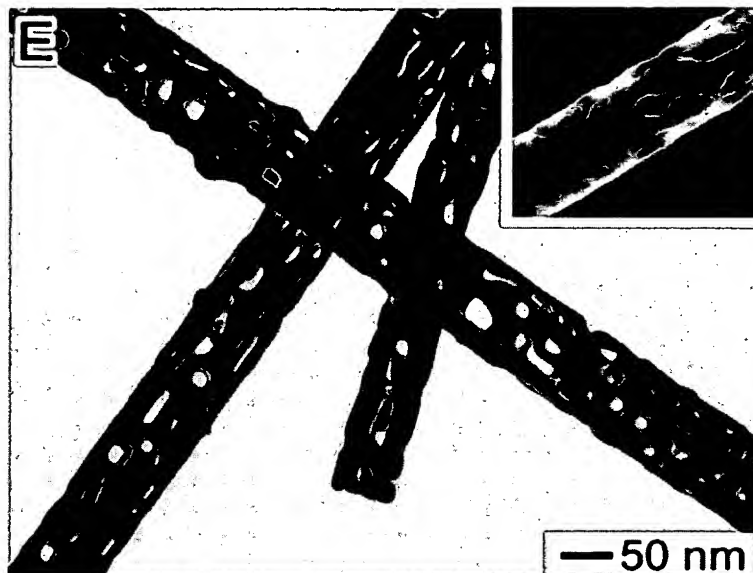


Fig. 12E

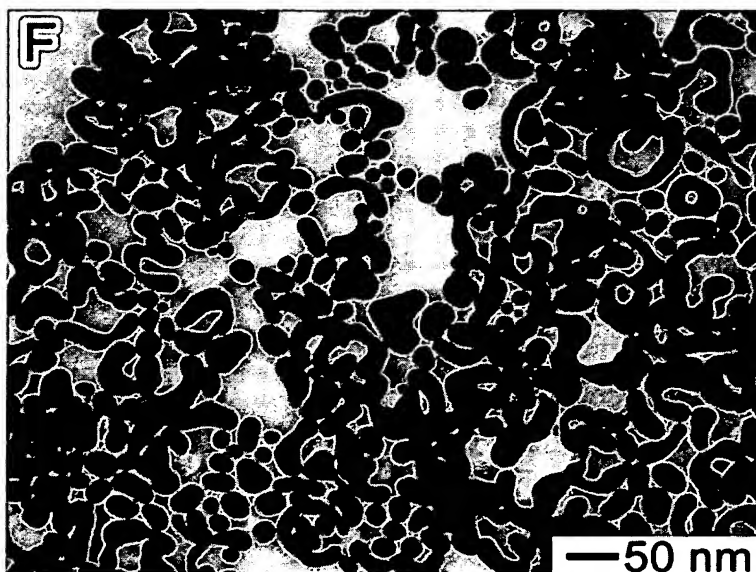
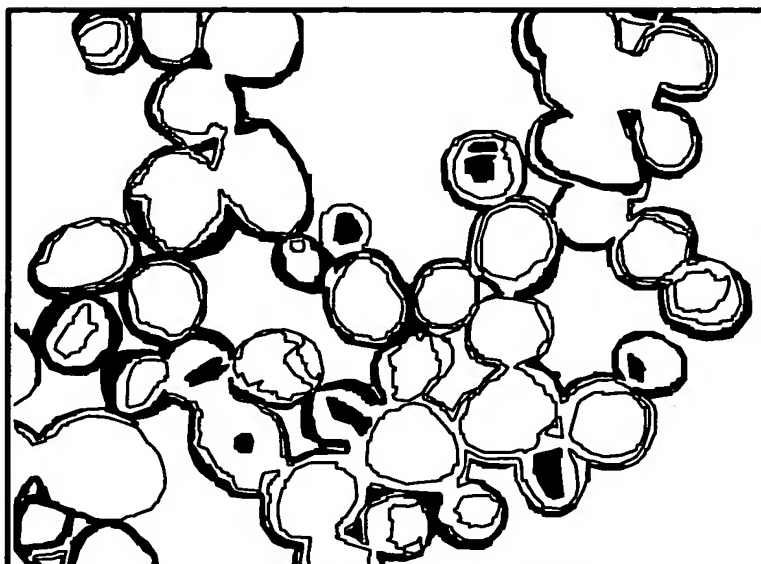


Fig. 12F



50 nm

Fig. 13A



50 nm

Fig. 13B

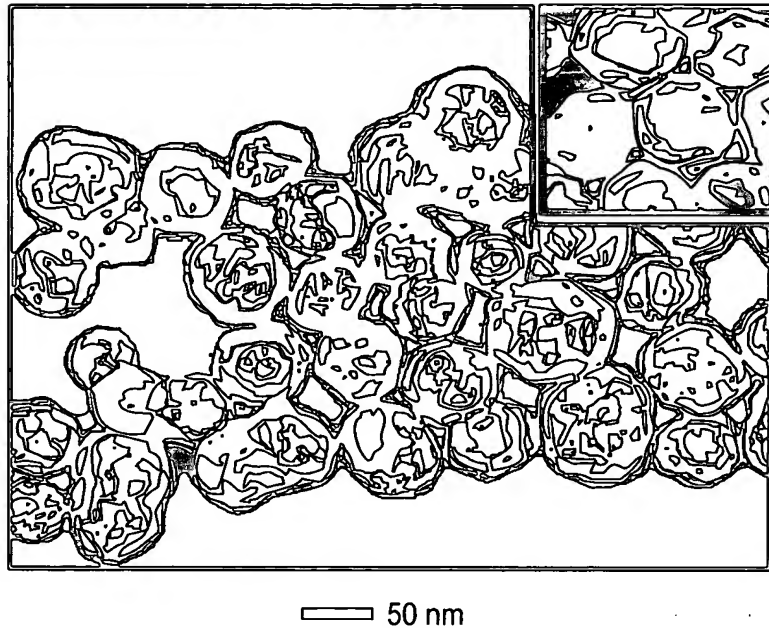


Fig. 13C

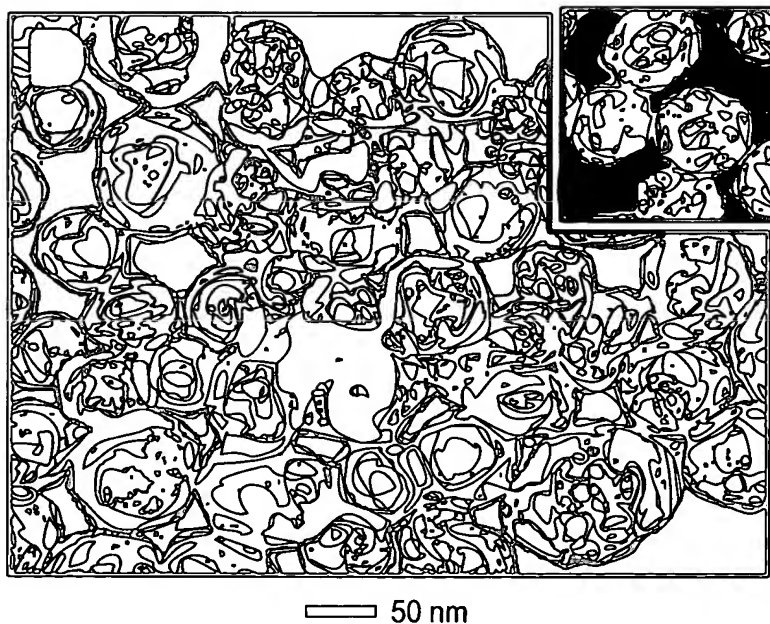
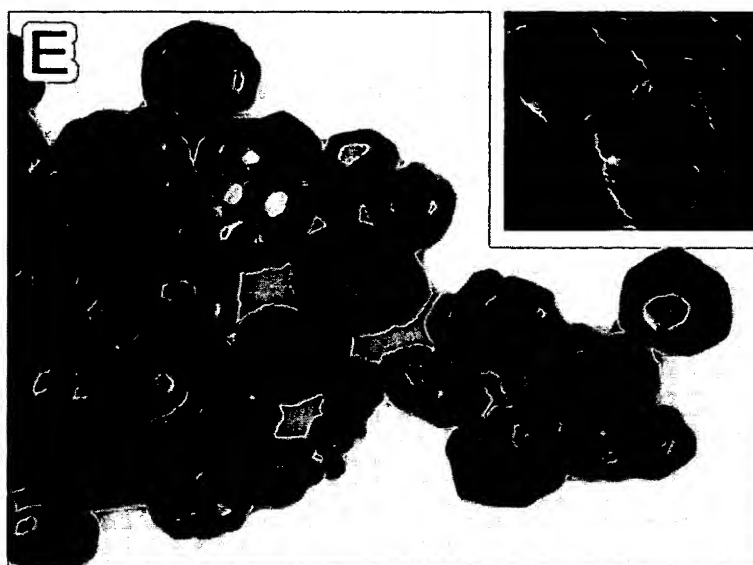
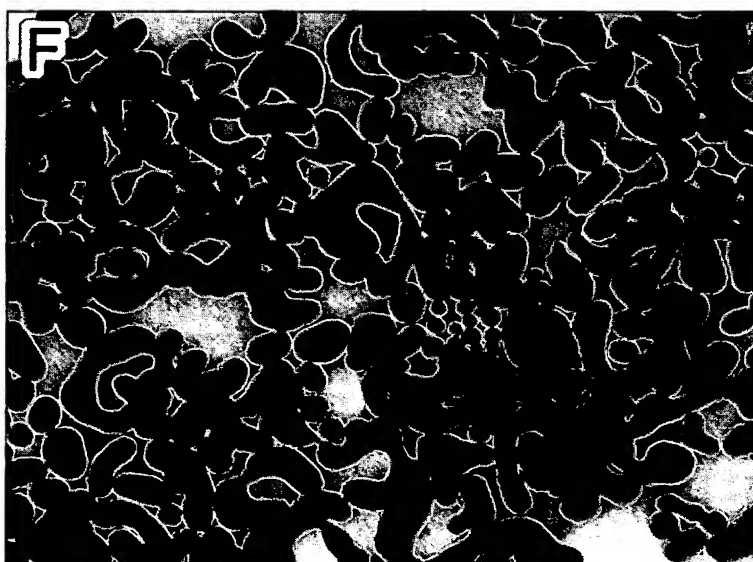


Fig. 13D



— 50 nm

Fig. 13E



— 50 nm

Fig. 13F

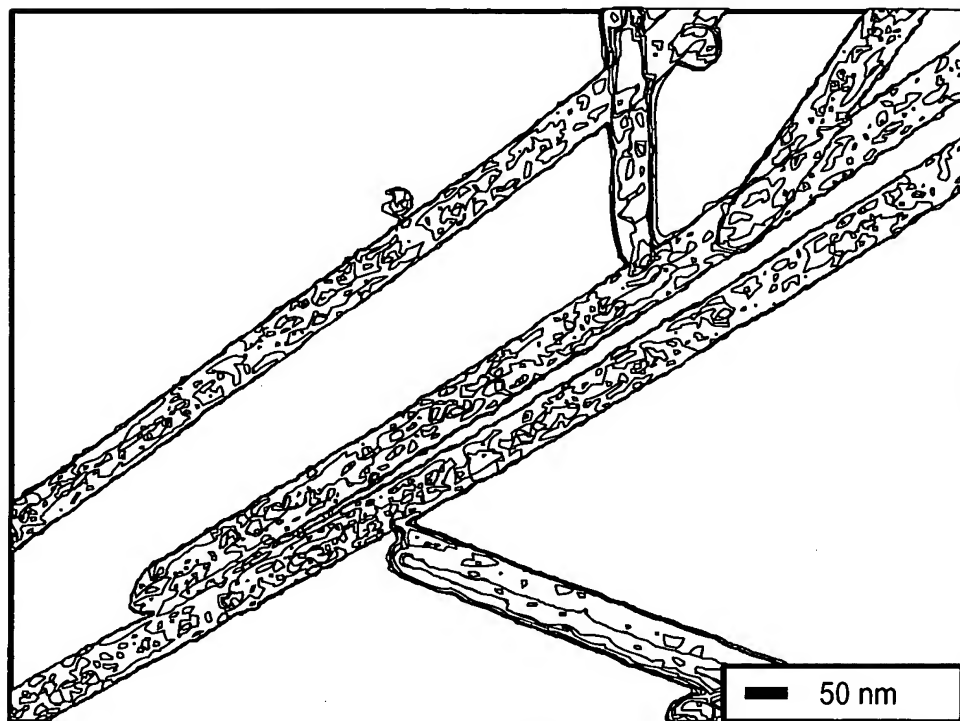


Fig. 14

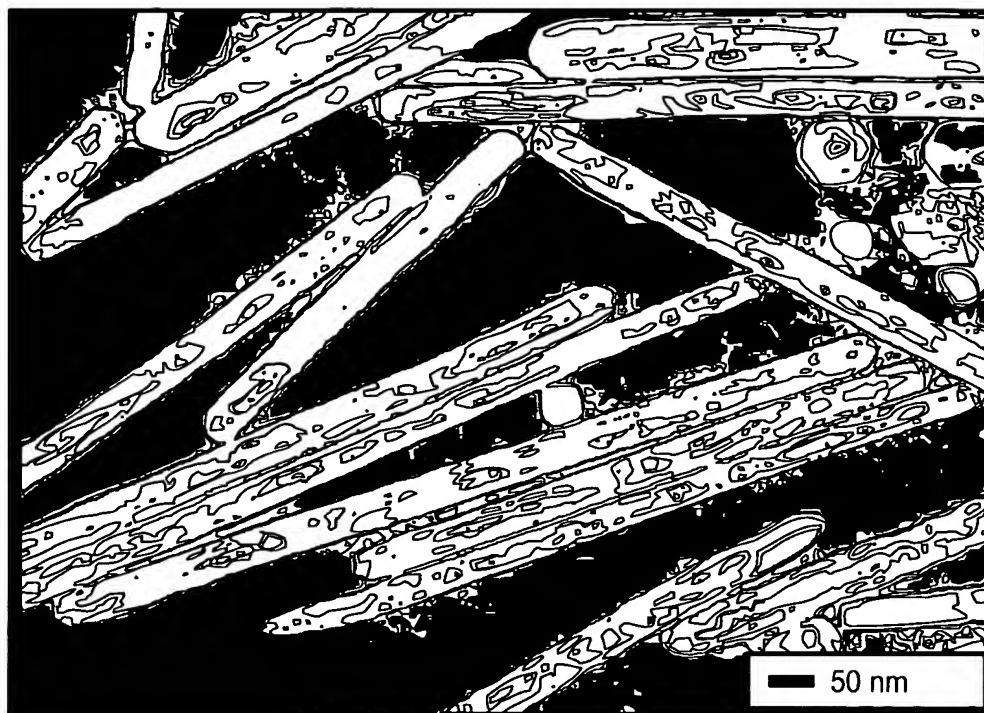


Fig. 15A

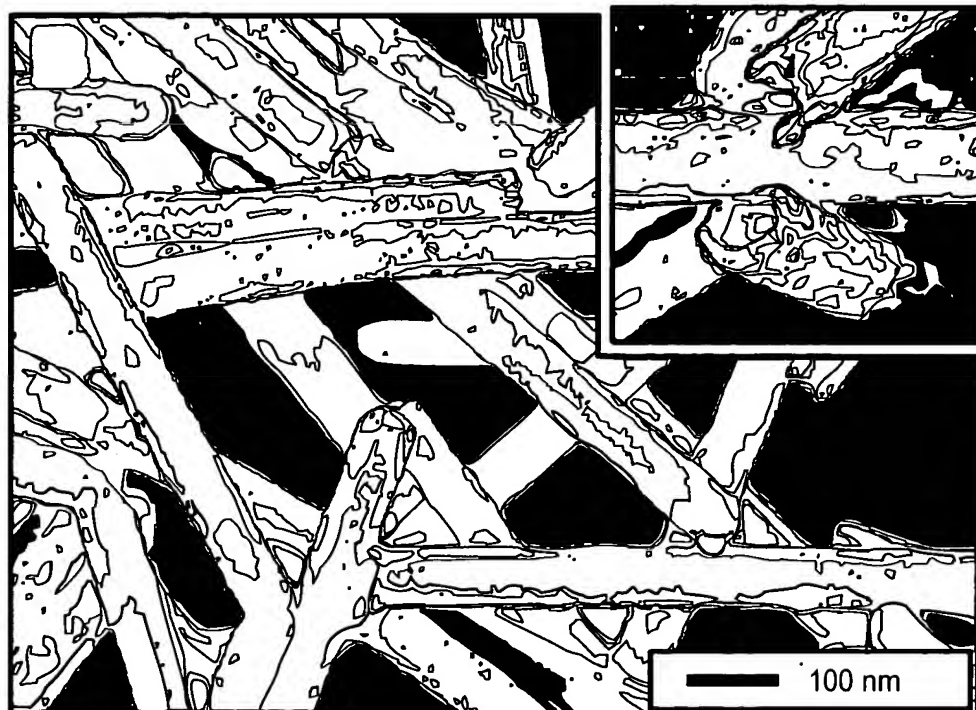


Fig. 15B

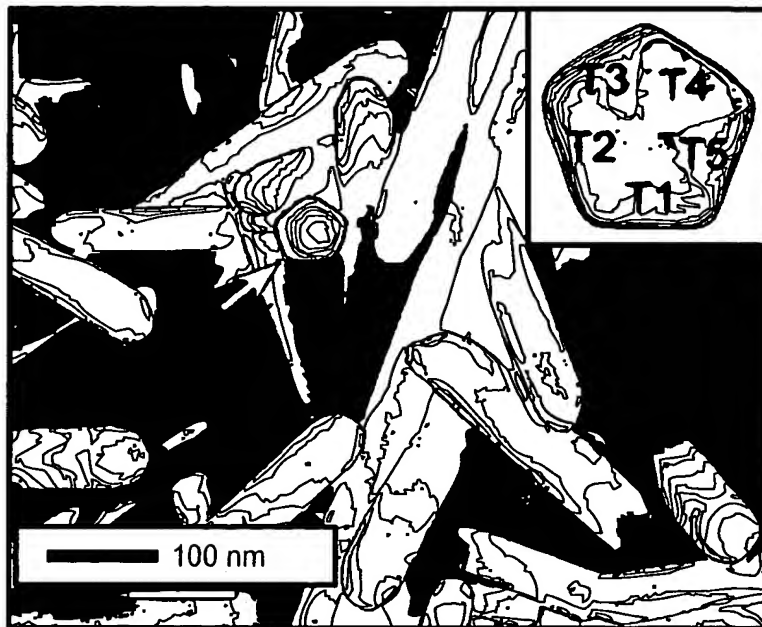


Fig. 16A

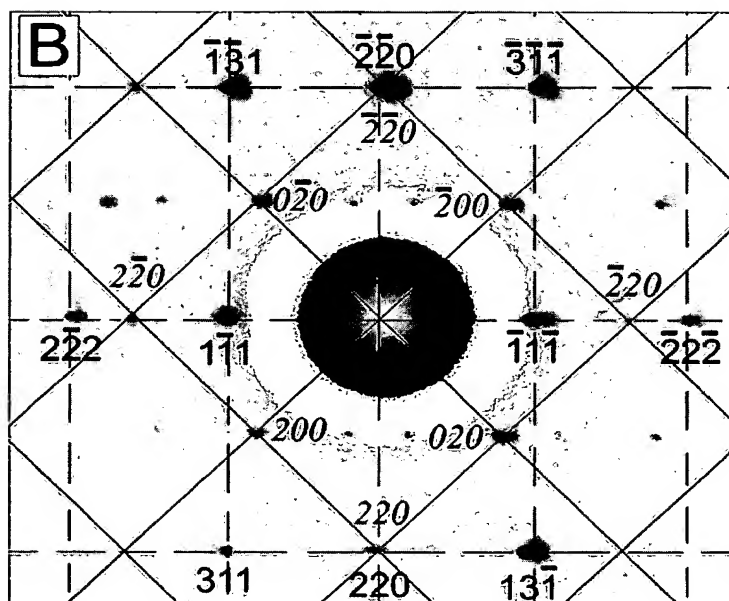


Fig. 16B

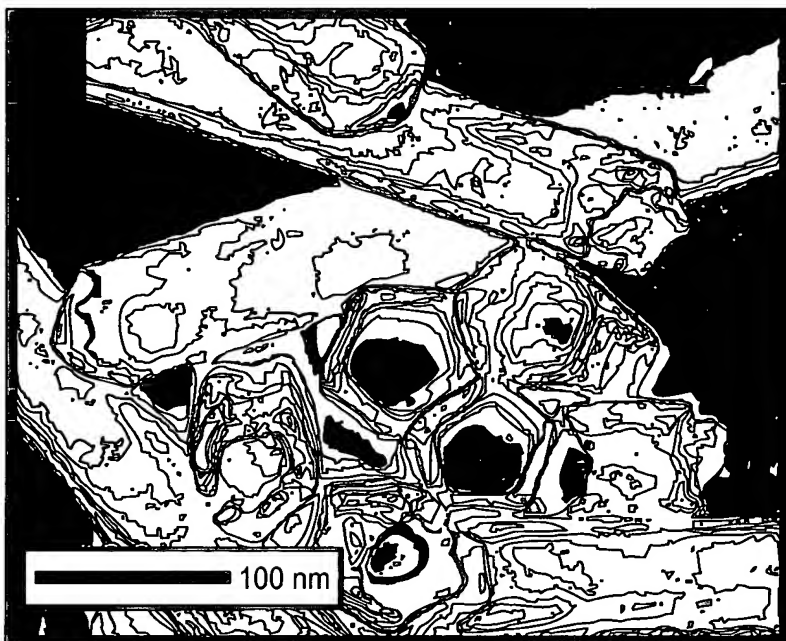


Fig. 16C

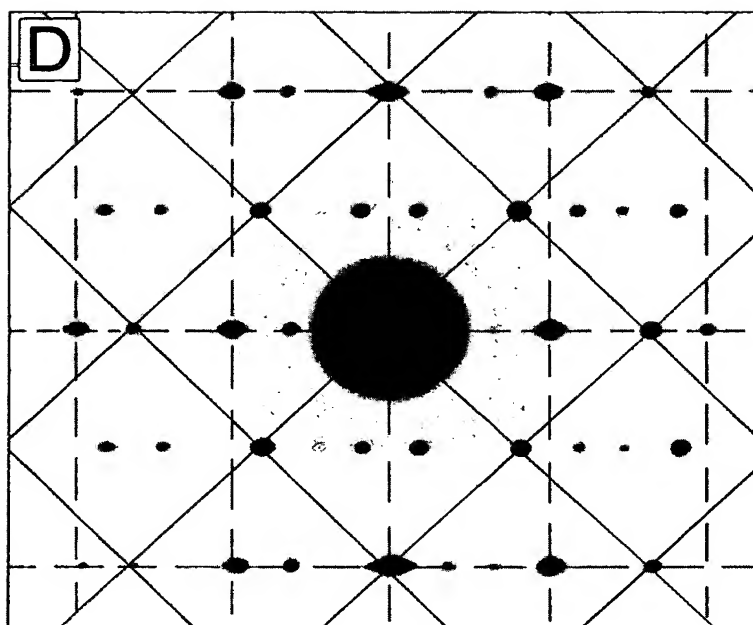


Fig. 16D

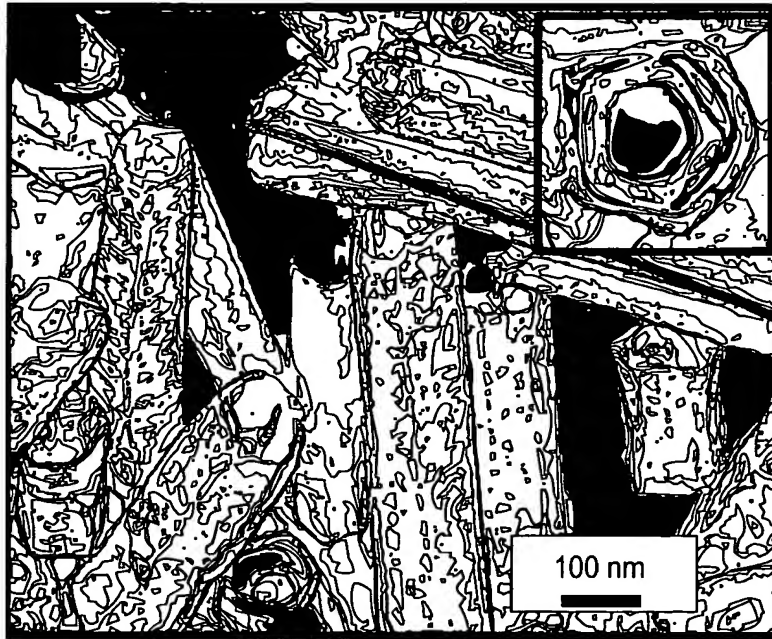


Fig. 16E

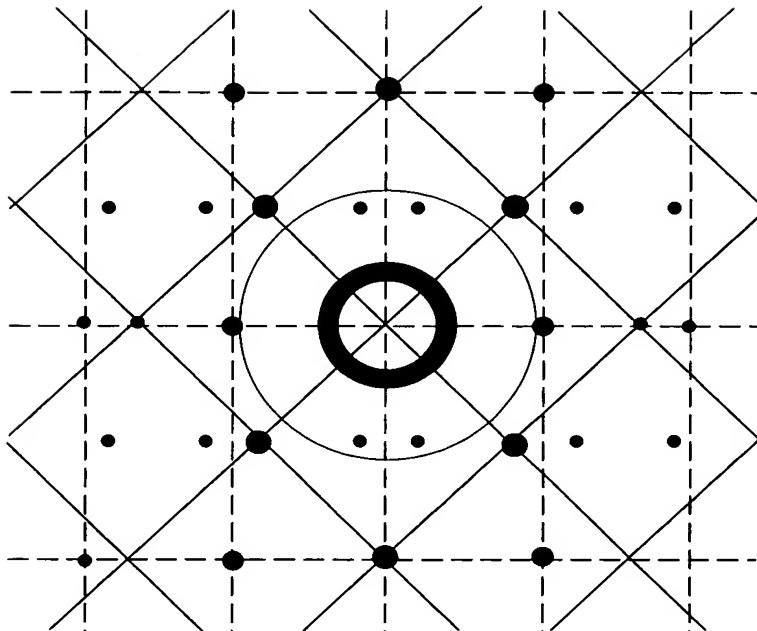


Fig. 16F

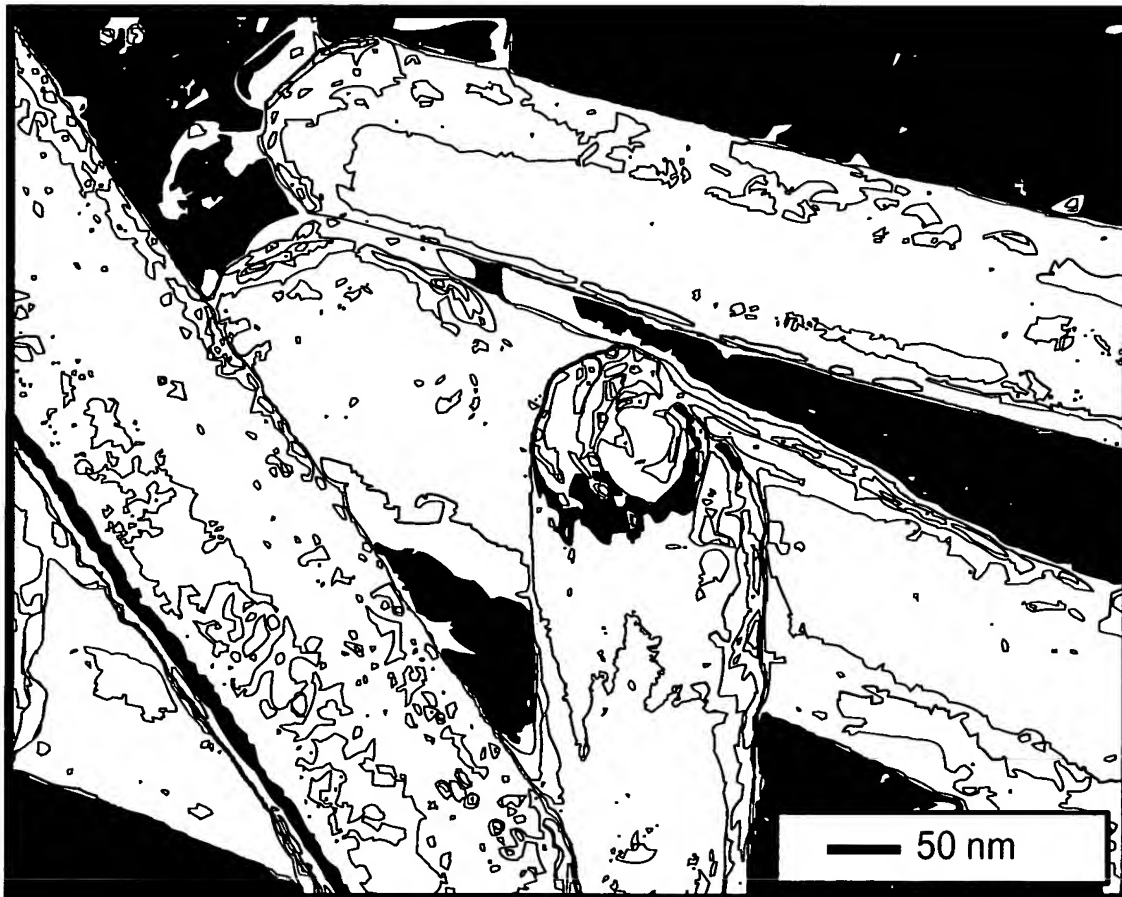


Fig. 17



Fig. 18

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